

Week 10

Light emitters 3

Outcoupling Strategies
Reliability

Chapter 6.6.2-6.7

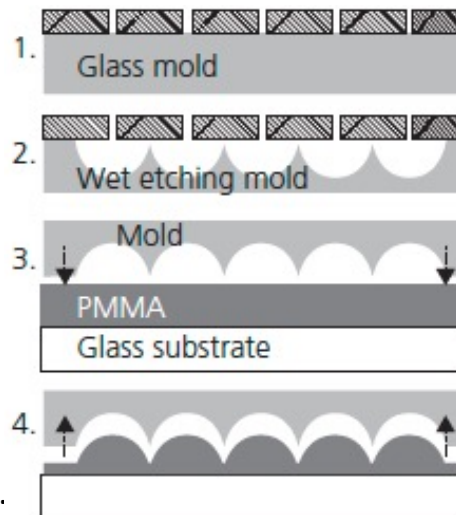
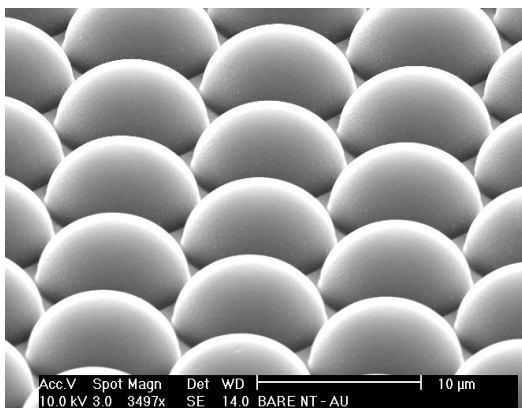


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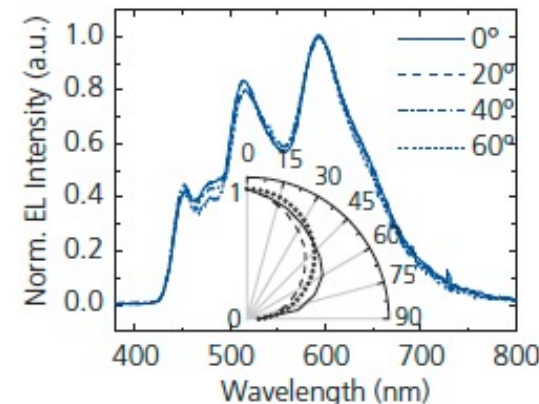
Substrate Mode Outcoupling: $\sim 2X$ Improvement

$\eta_{\text{ext}} \sim 40\%$

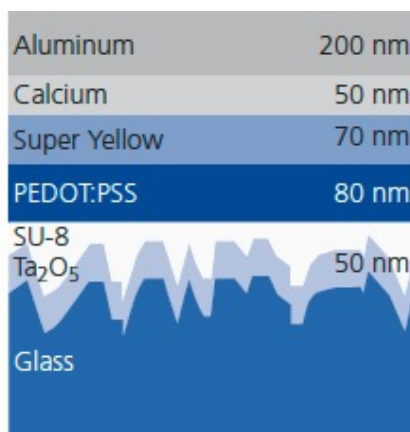
Microlens arrays: Polymer hemispheres much smaller than pixel



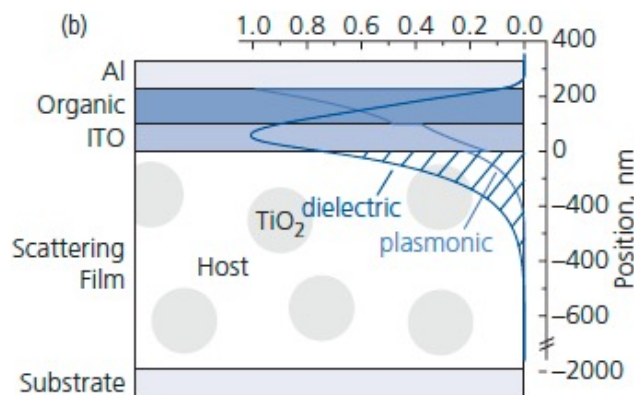
Fabrication sequence



Spectrum angle independent



Reidel, et al., Opt. Express 18 A631 (2010)



Chang, et al., J. Appl. Phys., 113 204502 (2013)

← Scattering and surface roughness also can reduce substrate modes

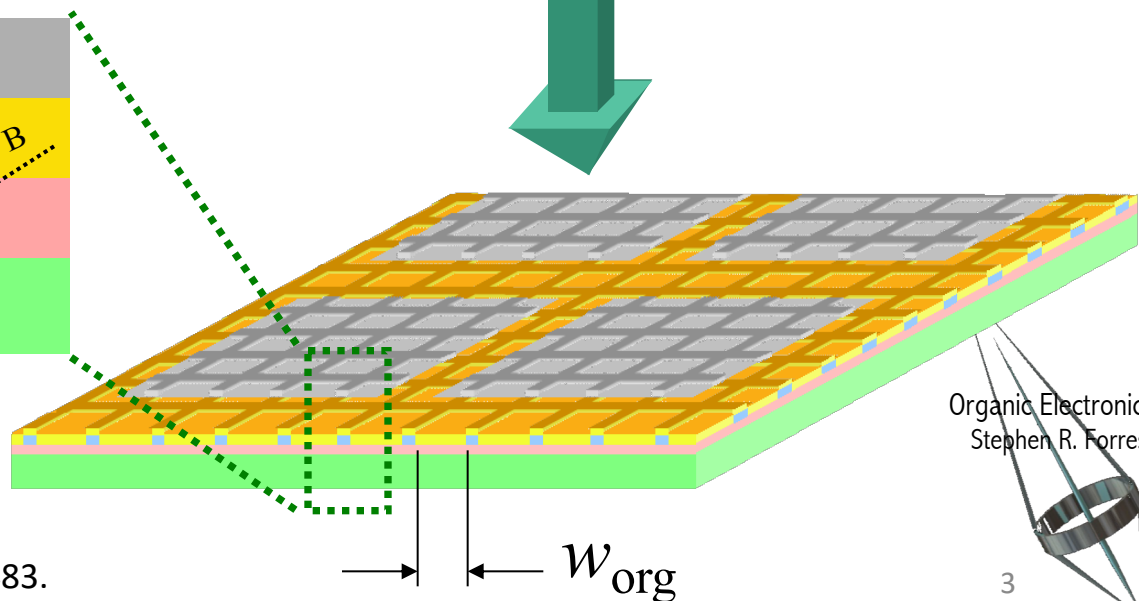
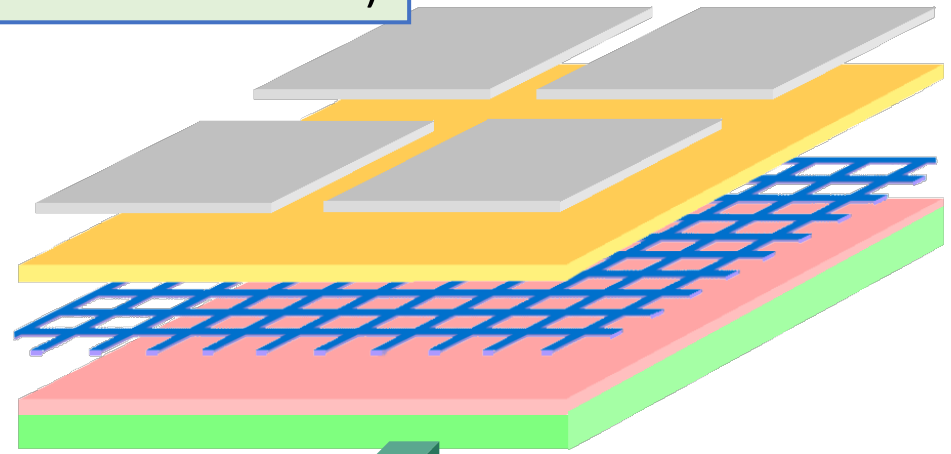
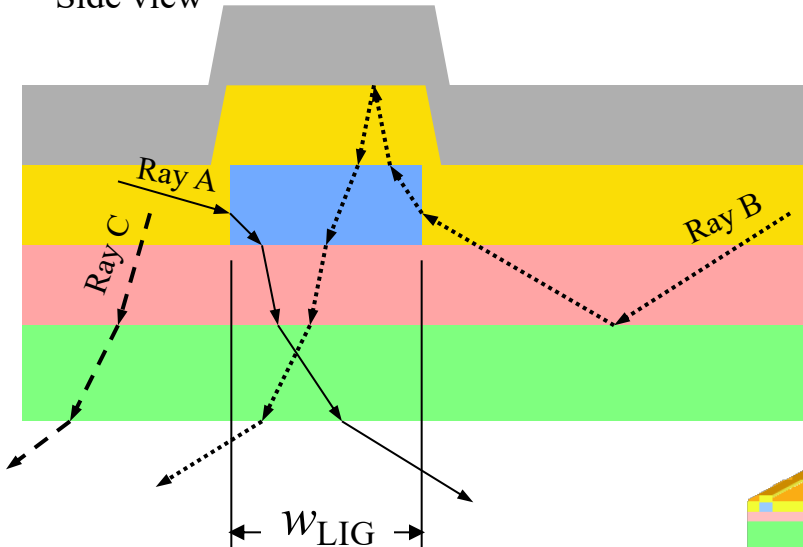
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Waveguide Mode Outcoupling: Embedded Low Index Grid

$\eta_{\text{ext}} \sim 60\%$ (incl. substrate modes)

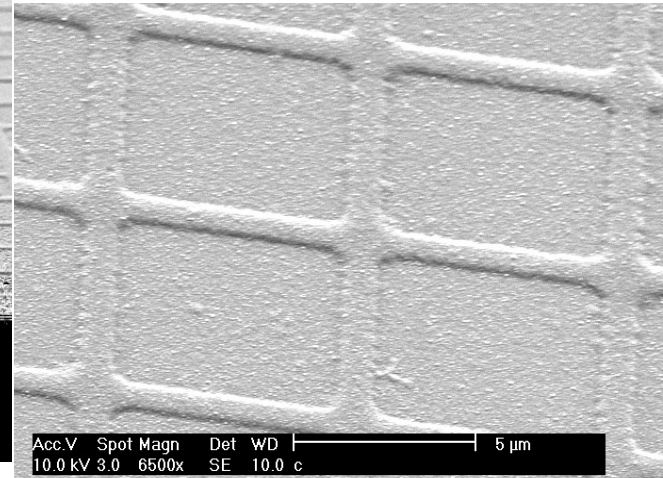
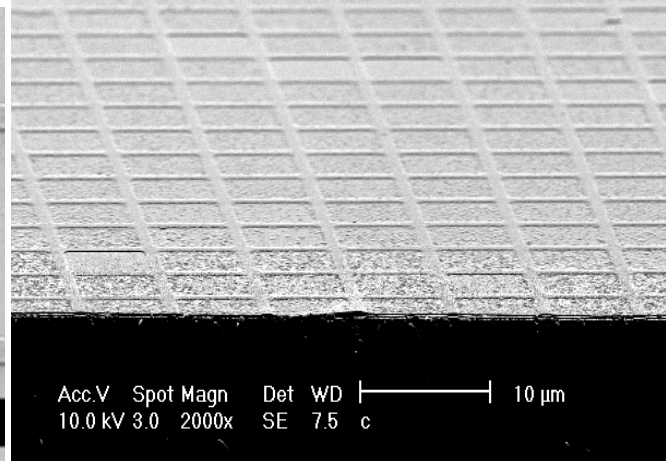
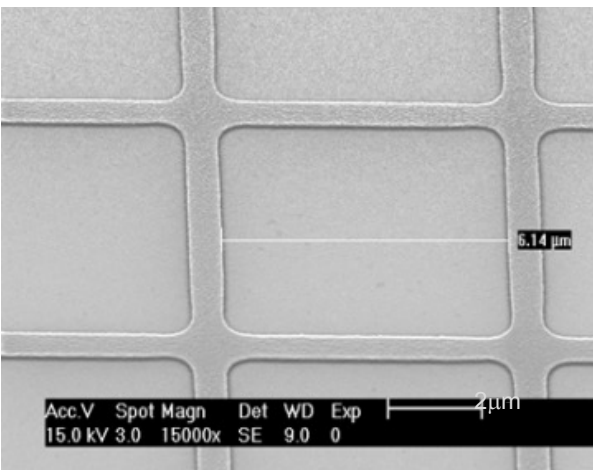
- Metal electrode pixel
- Organics
- Low-index grid
- ITO
- Glass substrate

Side view



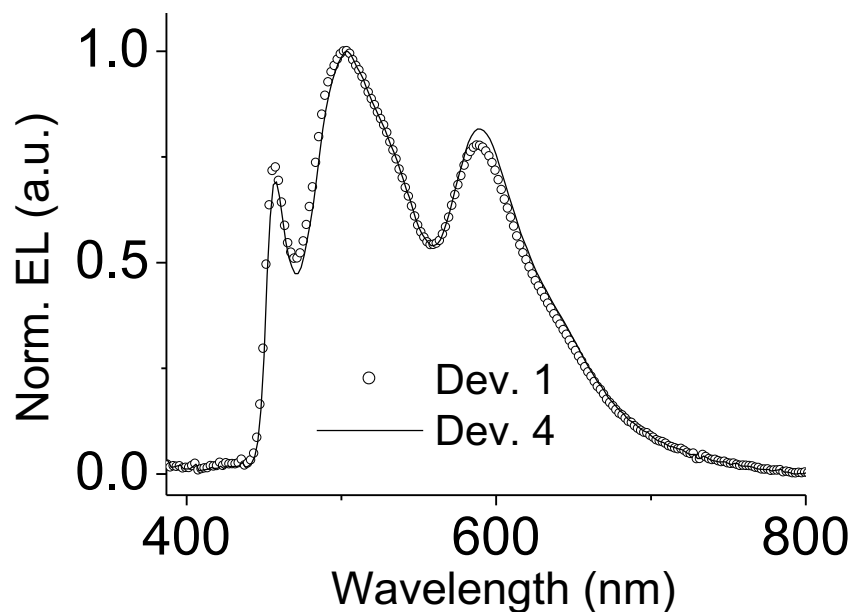
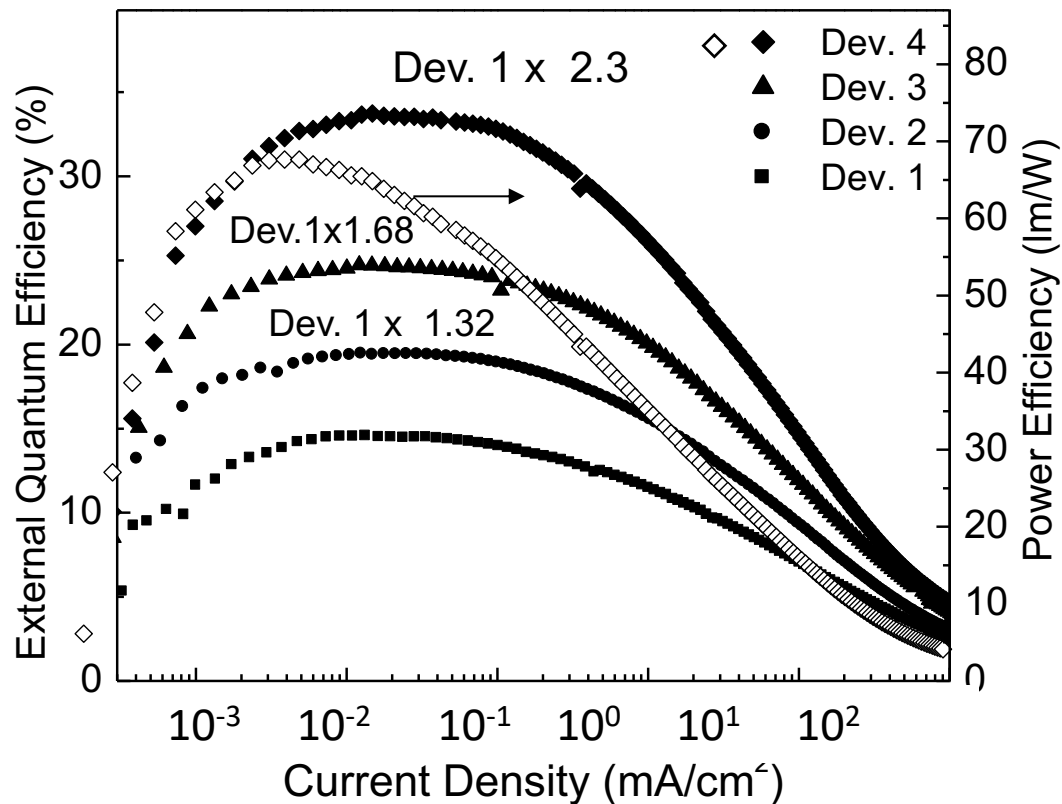
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Low Index Grid Images



- OLED \gg Grid size \gg Wavelength
- Embedded into OLED structure
- May partially decouple waveguide mode from SPPs

Hybrid WOLED Performance Using Embedded Grids + Microlens Arrays

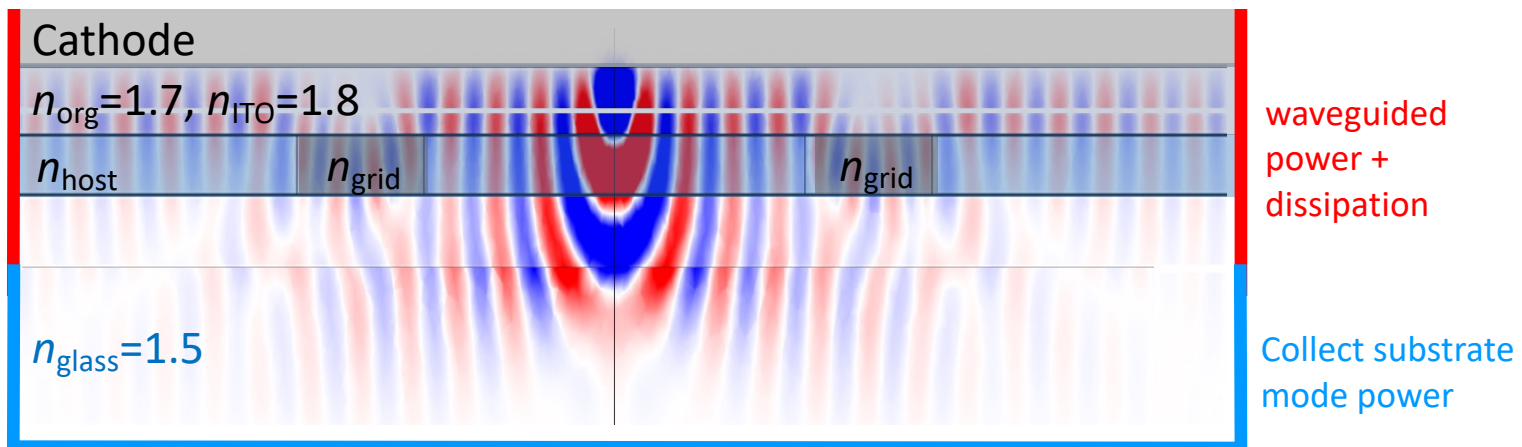
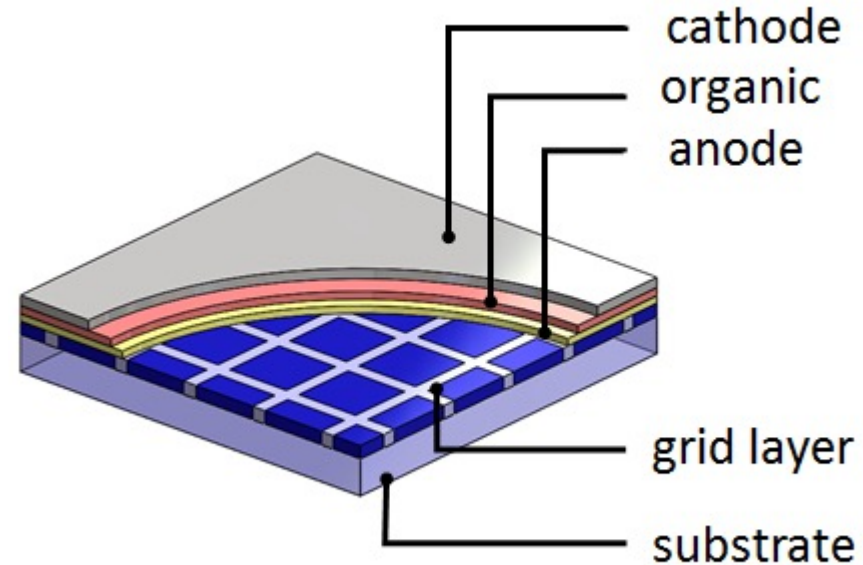


Method is Wavelength
Independent

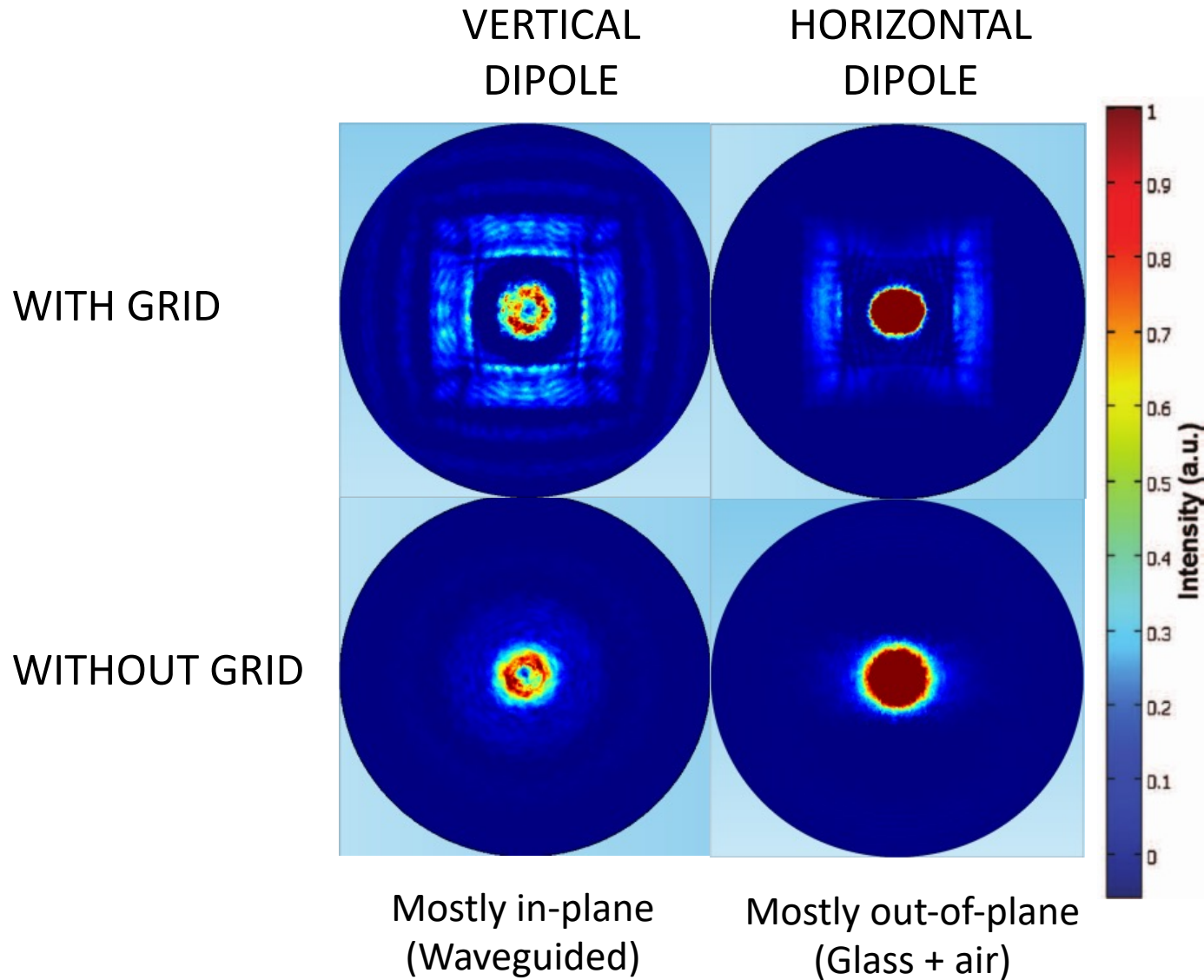
Device 1: Conventional
Device 2: LIG only
Device 3: Microlenses only
Device 4: LIG + Microlenses

A better approach: Sub-Anode Grid

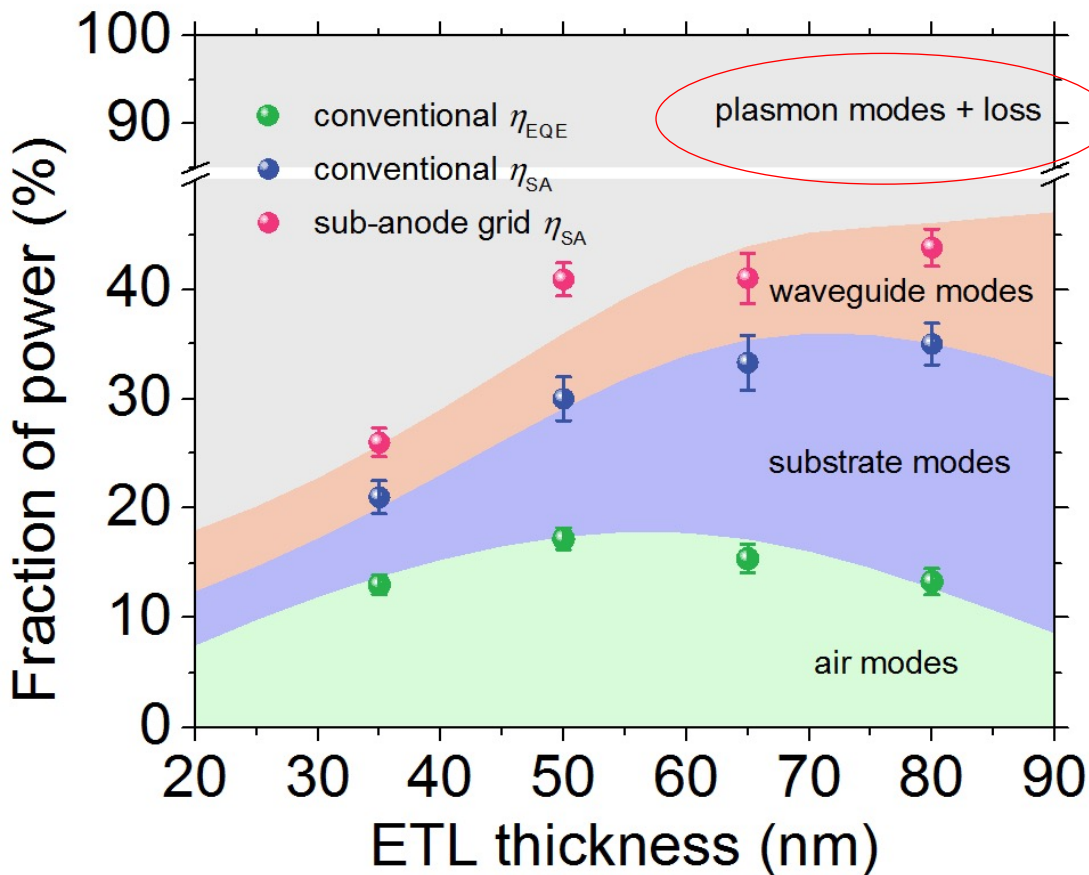
- ❑ A multi-wavelength scale dielectric grid between glass and transparent anode (sub-anode grid)
- ❑ The grid is removed from the OLED active region
- ❑ Waveguided light is scattered into substrate and air modes



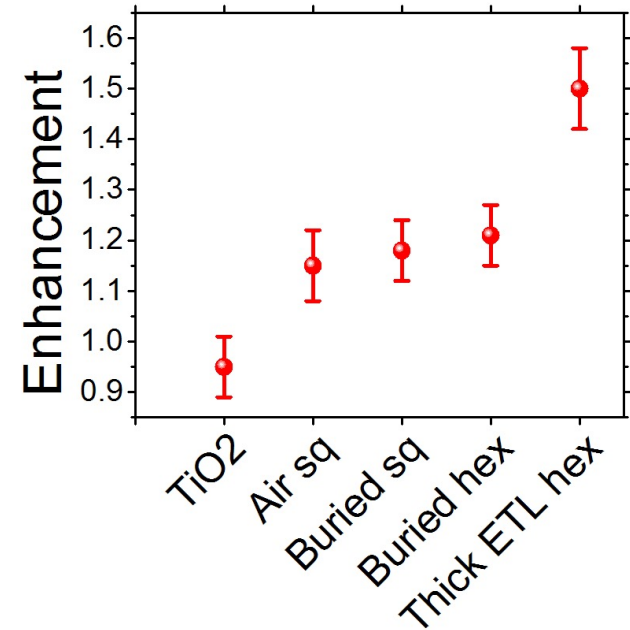
Emission field calculations



Optical Power Distribution



2nm MoO₃/40nm CBP/15nm CBP:Ir(ppy)₃/xnm
TPBi/1nm LiF/Al

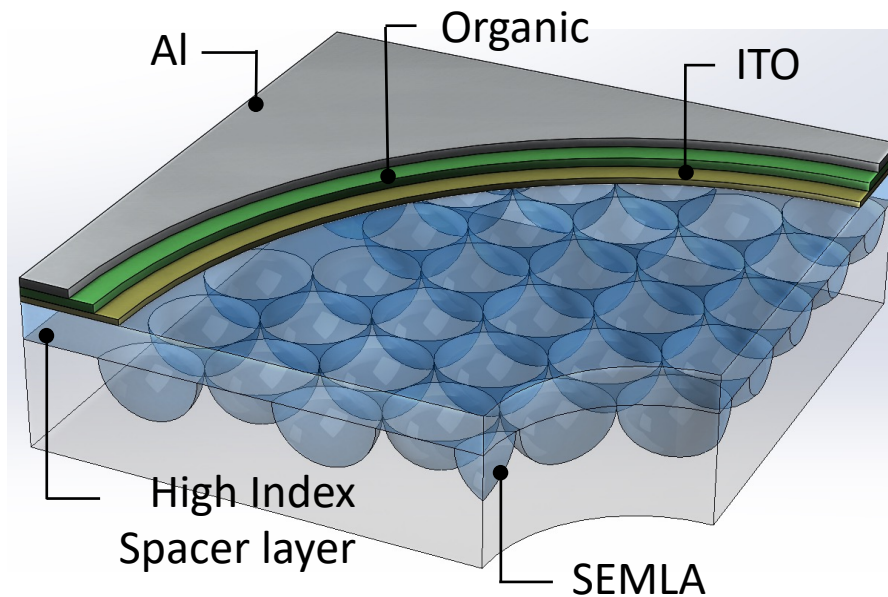


Thick-ETL organic structure:

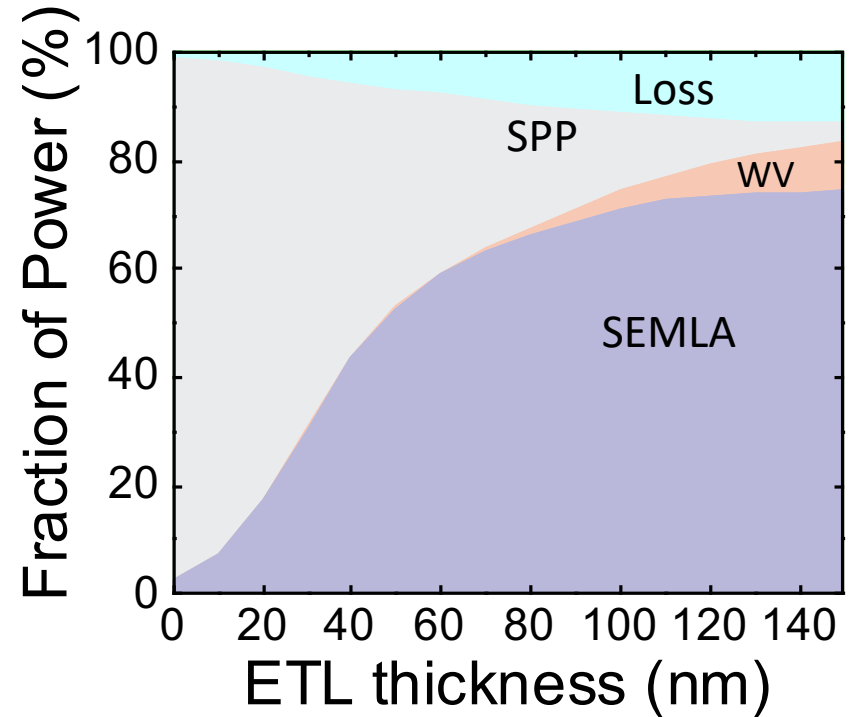
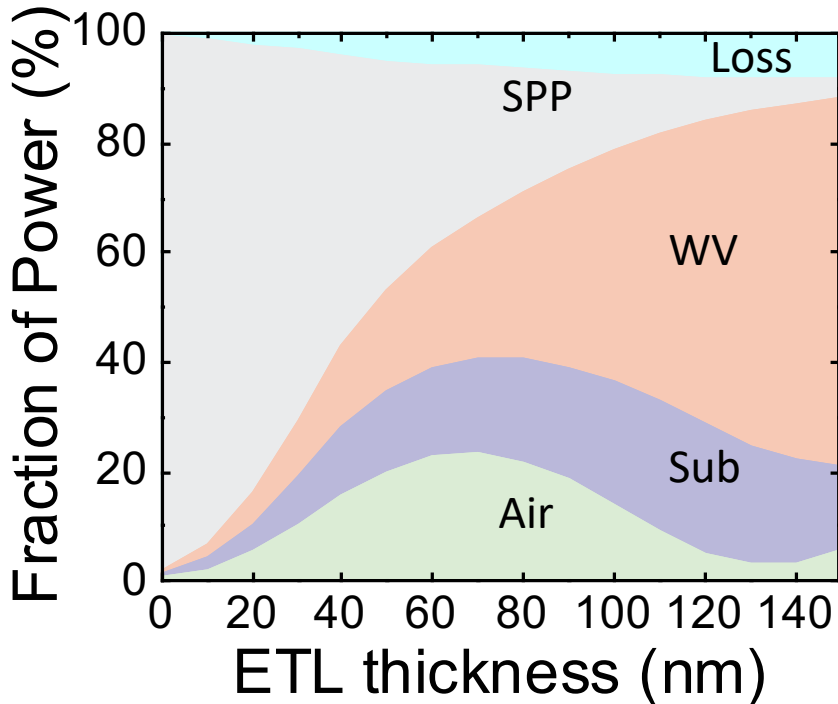
340nm grid/70nm ITO/2nm MoO₃/40nm
TcTa/15nm CBP: Ir(ppy)₃/10nm TPBi/230nm
Bphen:Li/Al

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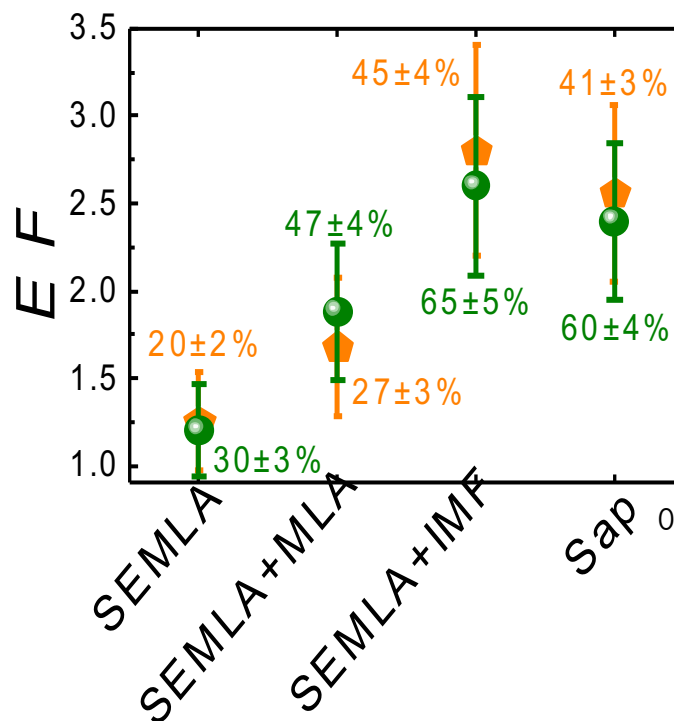
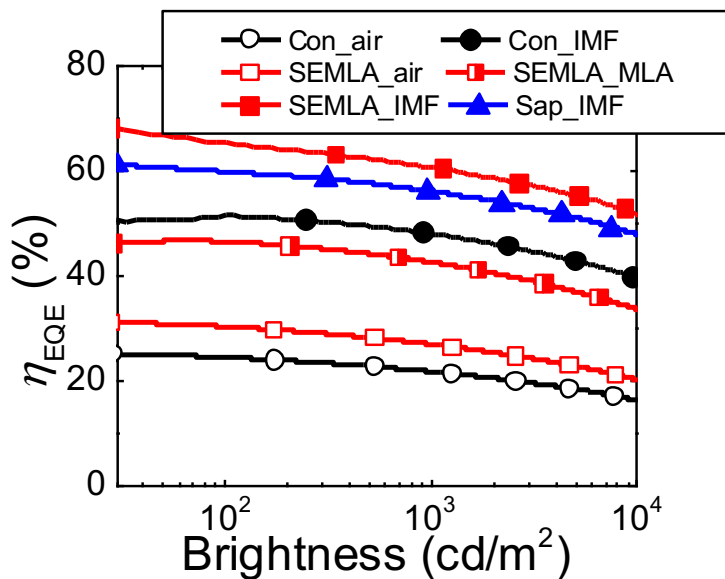
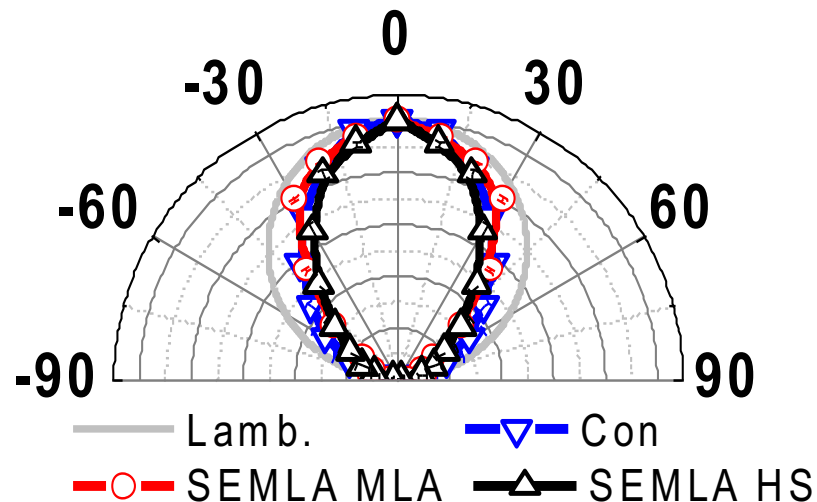
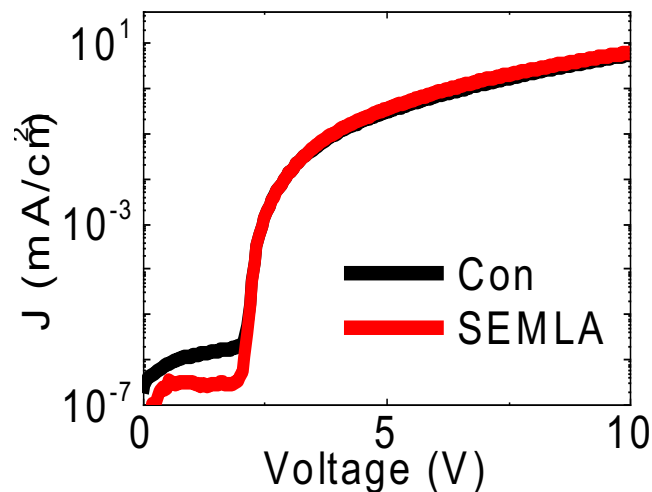
Getting All the Light Out: Sub-Electrode Microlens Array (SEMLA)



SEMLAs Change the Outcoupling Landscape



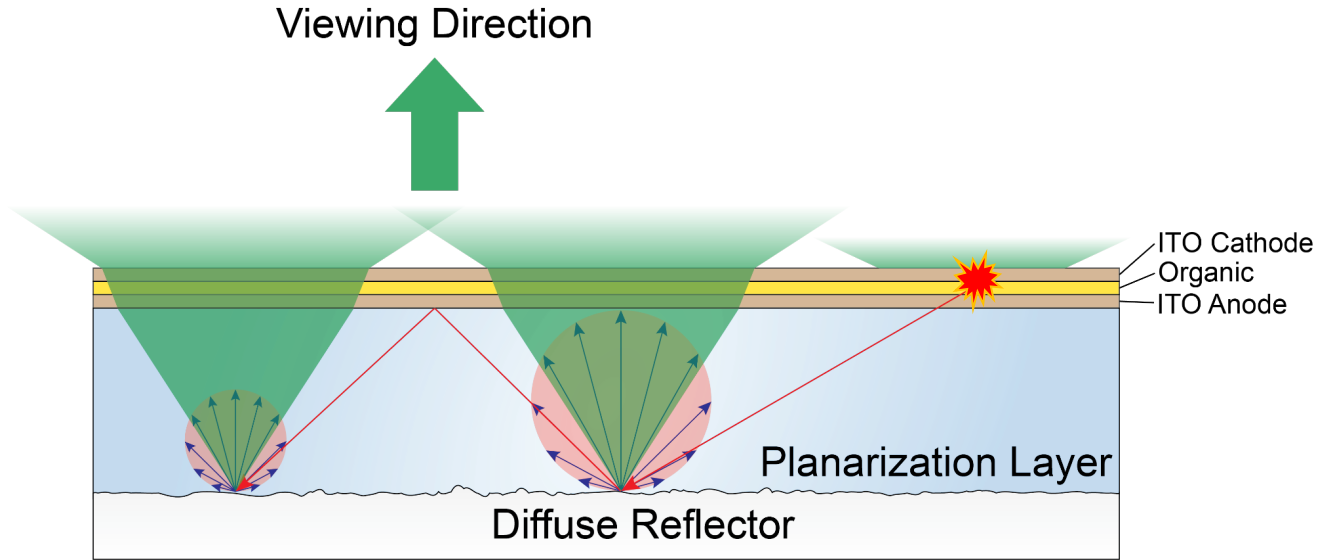
SEMLA Performance



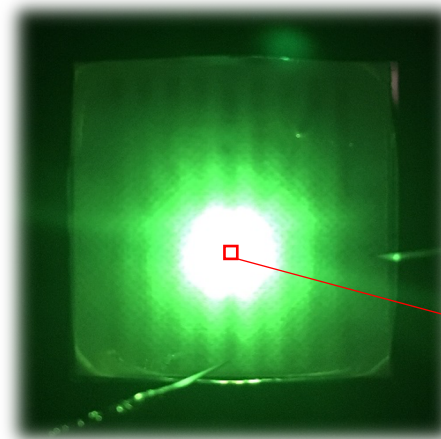
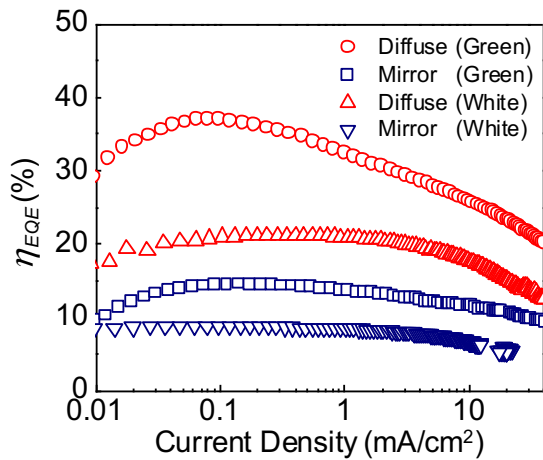
Qu, Y., et al. 2018. ACS Photonics, 5, 2453.

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Diffuse Reflectors: Low Cost & Simple



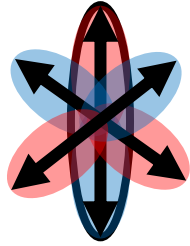
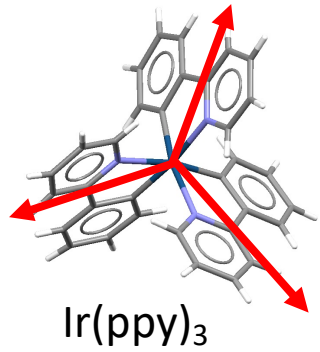
Teflon is the best diffuse dielectric reflector



PHOLED
Active Area

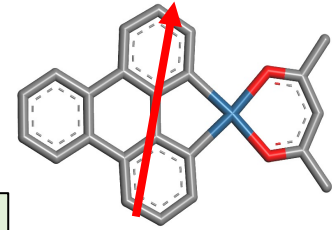
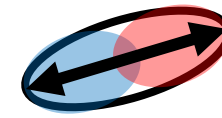
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Outcoupling Enhancements by Molecular Orientation

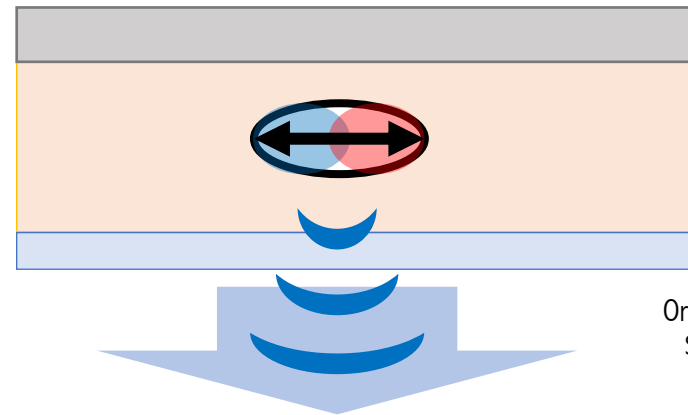
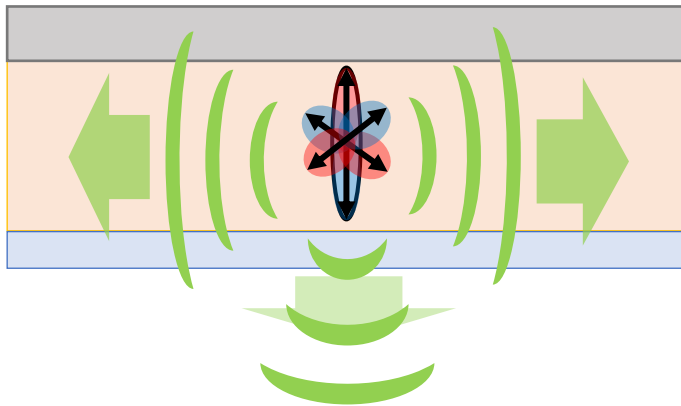
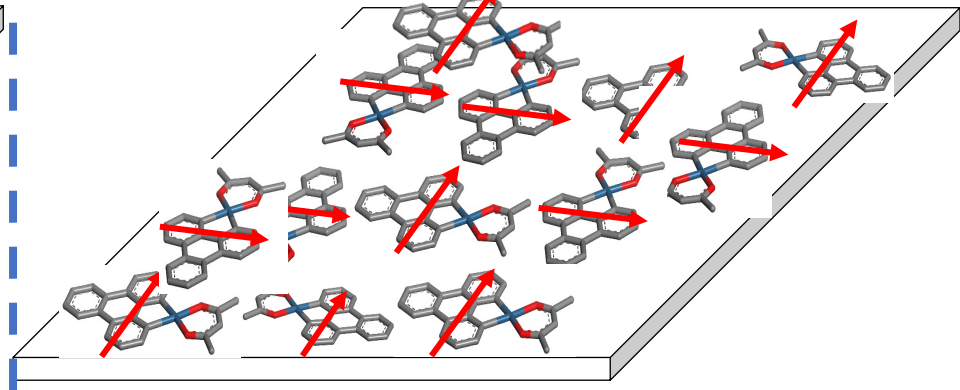
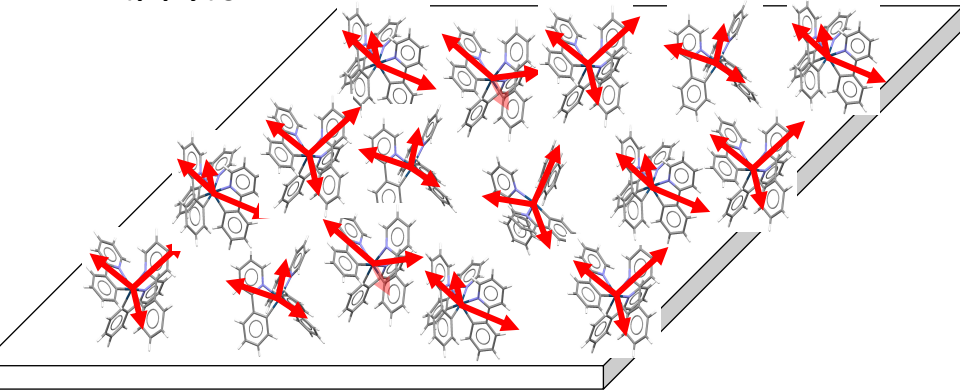


Isotropic
Orientation

Horizontal
Orientation

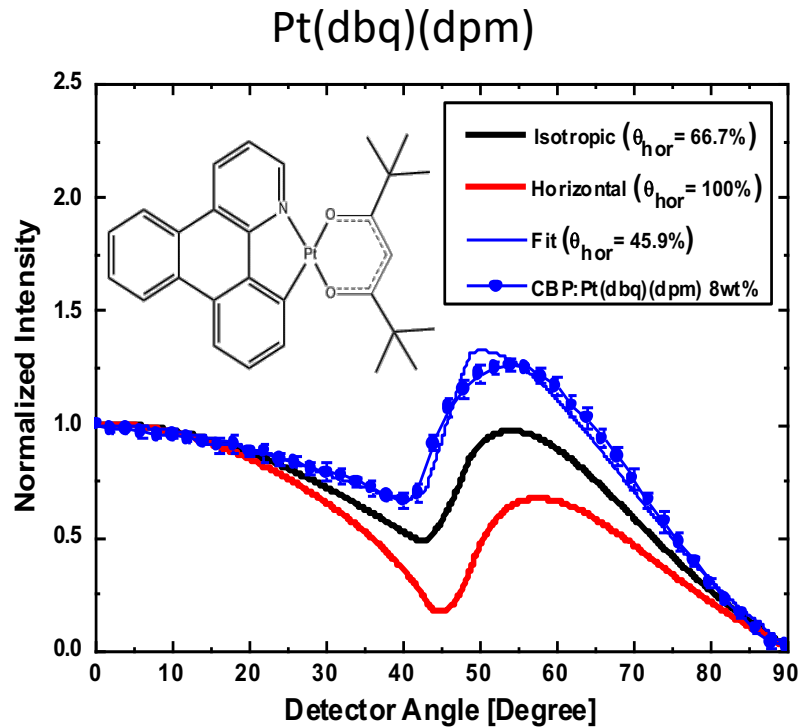
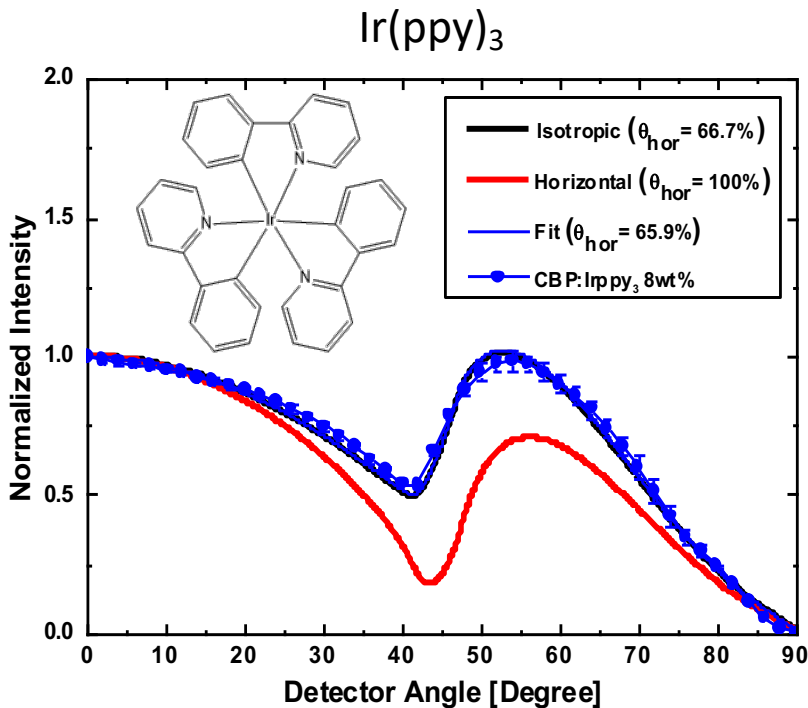


Prevents coupling to SPPs
and waveguide modes



Planar molecules (e.g. Pt-complexes) more likely to align than octahedral (tris-Ir complexes)

Example results



Ratio of light emitting by vertical to horizontal dipoles: $\Theta = \frac{TM_{\parallel}}{TE_{\perp} + TM_{\perp} + TM_{\parallel}}$

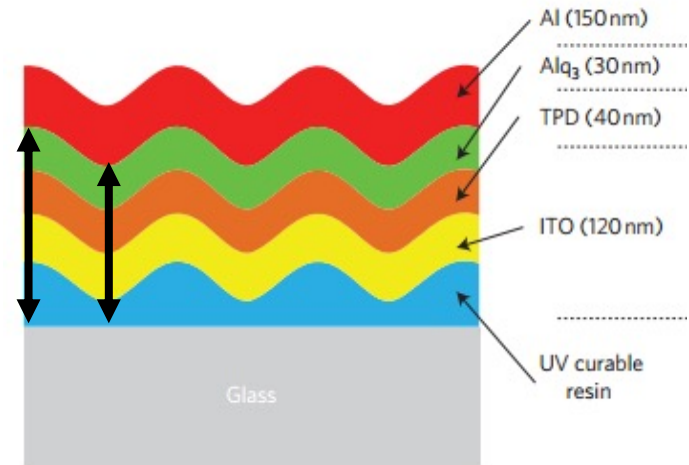
Approach challenges

- Added constraints on molecular design
- Added constraints on process (growth) conditions: may not align as expected
- Added constraints on device architecture
- Alignment is never “perfect”: only modest improvements

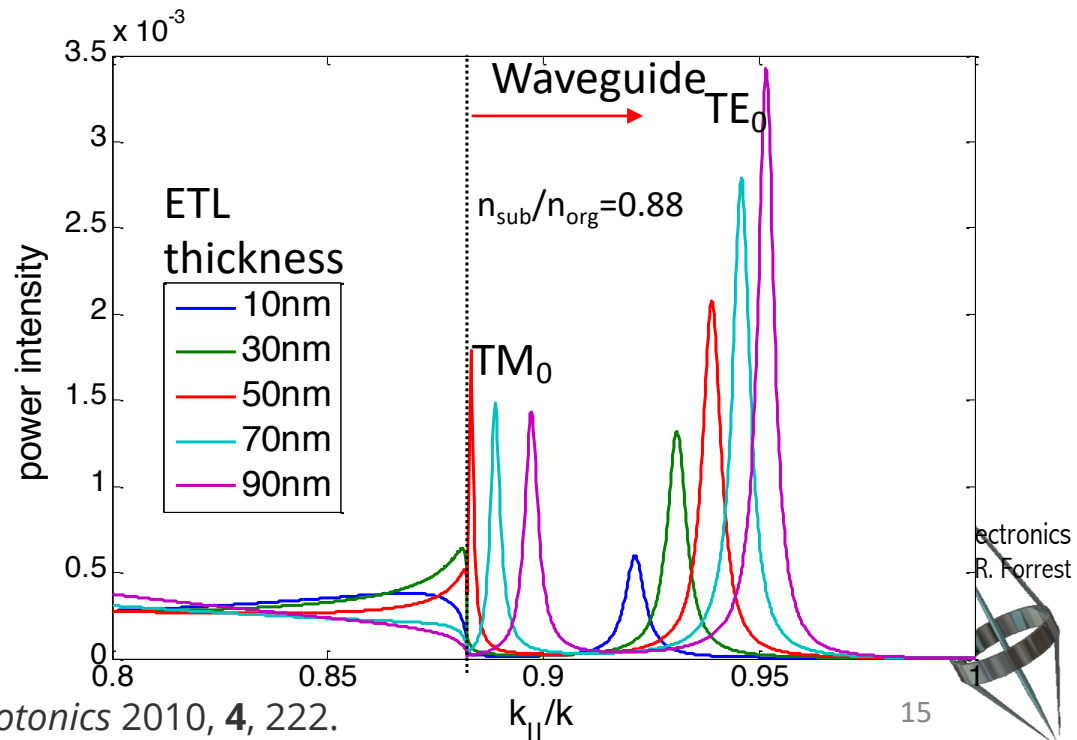
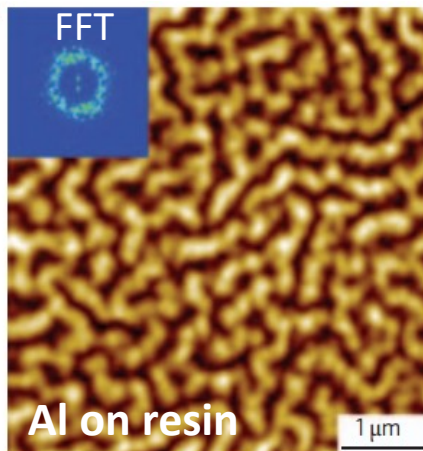


Substrate Corrugations Can Outcouple Waveguide Modes

- Waveguide thickness varies due to the corrugation.
- As the thickness changes, the mode distribution changes.
- When the waveguided power travels from thin to thick areas, the k vector needs to change direction to keep “being trapped”. Otherwise, the light is extracted.



A possible approach: Surface buckling?



Reliability Testing Methodologies

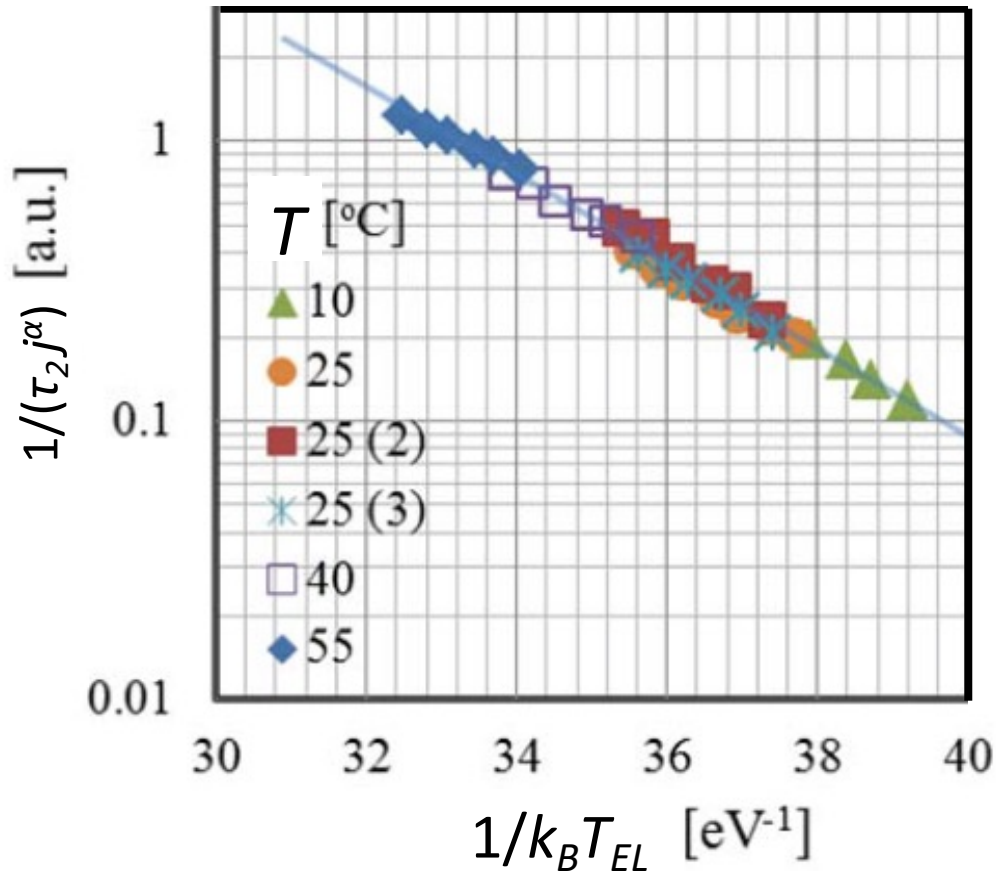
- Need to set clear metrics for failure
 - Example: Operating time for initial luminance (L_0) to decrease 10% from its initial value (called T90, or LT90)
 - Employ a population of equivalent devices and monitor their performance parameter (e.g. luminance) under normal operating conditions
 - If degradation slow, then an empirical degradation relationship is determined to extrapolate time to failure
 - Example: **Stretched exponential function**:
$$L(t) = L_0 \exp(-t/\tau)^\beta \quad \tau, \beta = \text{empirical constants}$$
- If degradation too slow, need to accelerate via increased T or L_0 .
 - Accelerated conditions must not introduce new failure modes
 - Need empirical relations to normalize lifetime to standard operating conditions (called **acceleration factors**)

$$LTx(L_0) = LTx(L_{0ist}) \cdot \left[\frac{L_{0ist}}{L_0} \right]^n \quad n = \text{empirical acceleration factor}$$

Accelerated Degradation Methodologies

Sum of lifetimes alternative empirical relation):

Example data: Green PHOLED

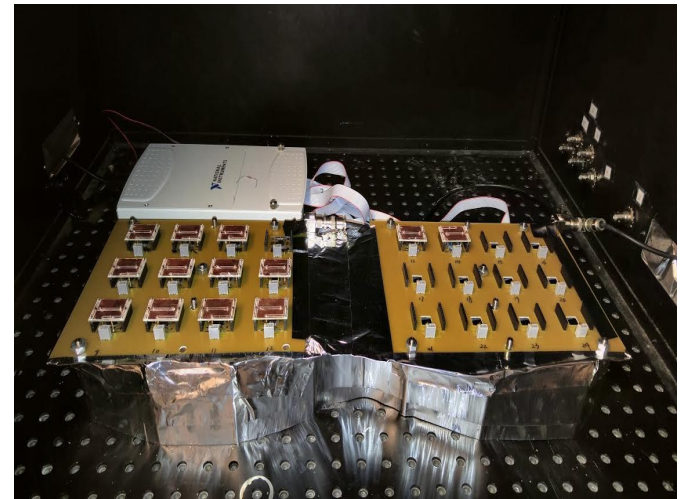


$$L(t)/L_0 = \lambda \exp(-t/\tau_1) + (1-\lambda) \exp(-t/\tau_2)$$

Burn-in
Long term decay

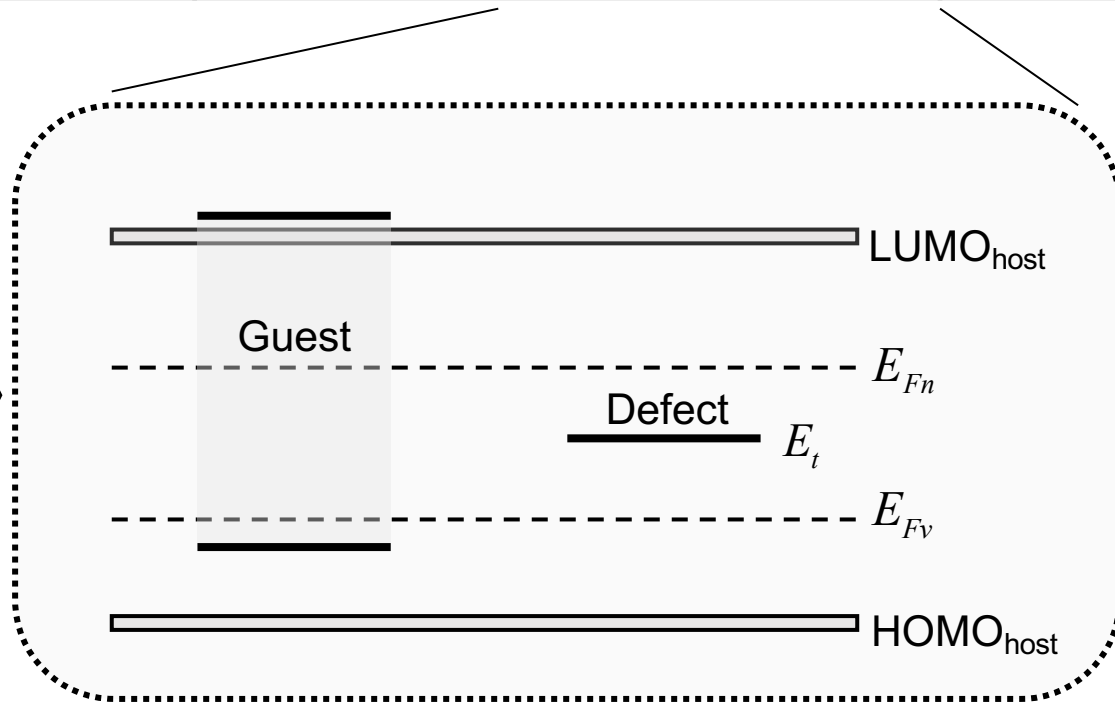
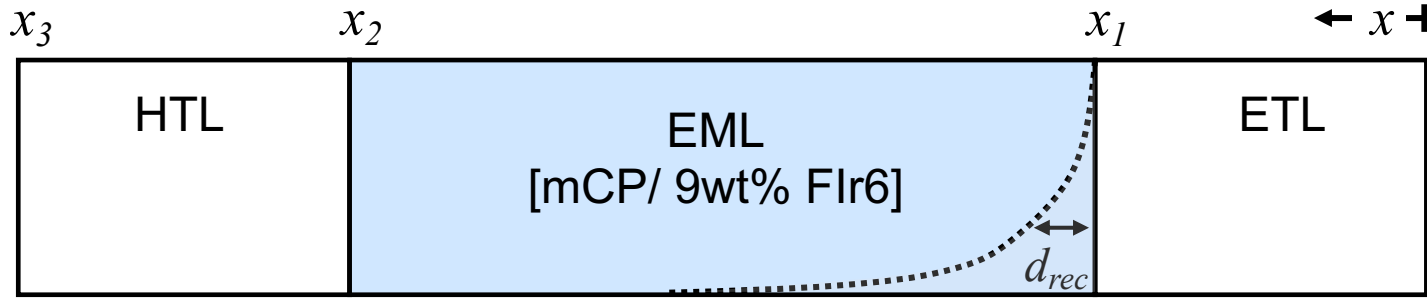
$$\frac{1}{\tau_2} = K'' j^\alpha \exp(-\Delta E_{A0}/k_B T)$$

ΔE_{A0} = thermal activation of degradation
 α = current acceleration factor



Measuring populations of identical devices

Intrinsic Lifetime Limits of OLEDs

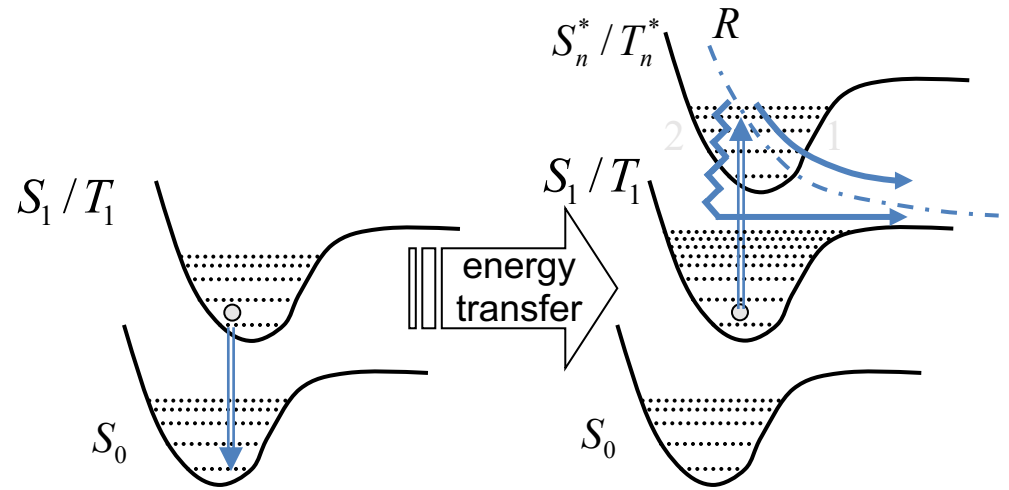


Energy Scale
 Red light: ~ 2 eV
 Green light: ~ 2.3 eV
 Blue light: ~ 2.9 eV

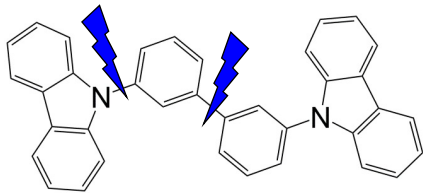


Degradation Routes

- Energetically Driven
 - Lifetime: $R > G > B$
- Two particle interactions lead to luminance loss
 - Exciton on phosphor, polaron on host
 - Exciton-exciton also possible



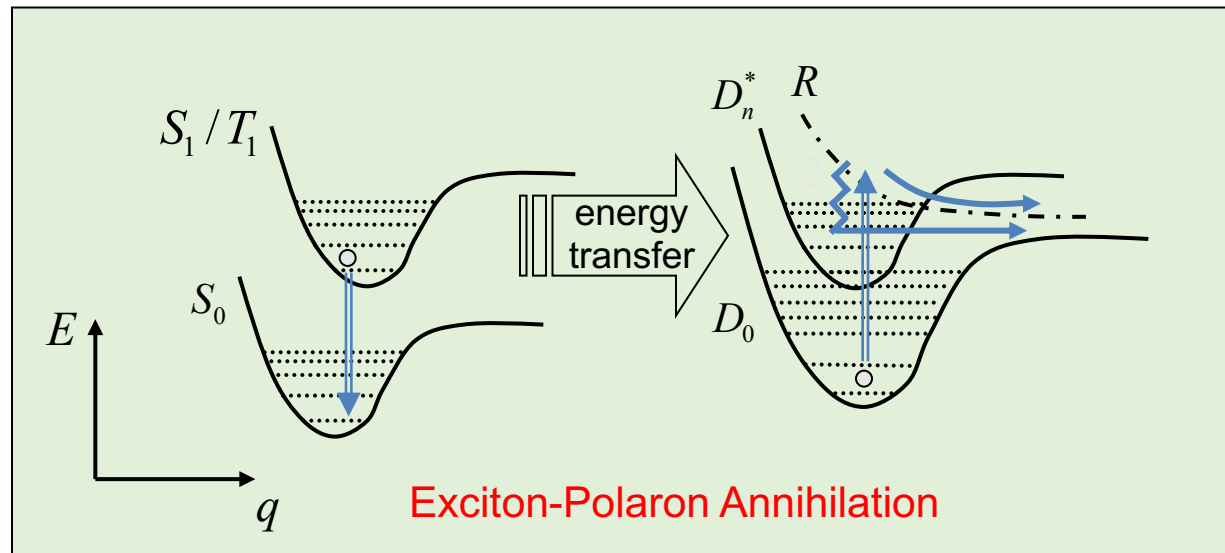
Exciton-Exciton Annihilation



Bond	BE(eV)	Bond	BE(eV)
C-C	3.64	N-N	1.69
C-H	4.28	N-O	2.08
C-O	3.71	N-H	4.05
C-N	3.04	O-O	1.51
C-F	5.03	H-H	4.52

Bond cleavage

Broken bonds? → Defects!

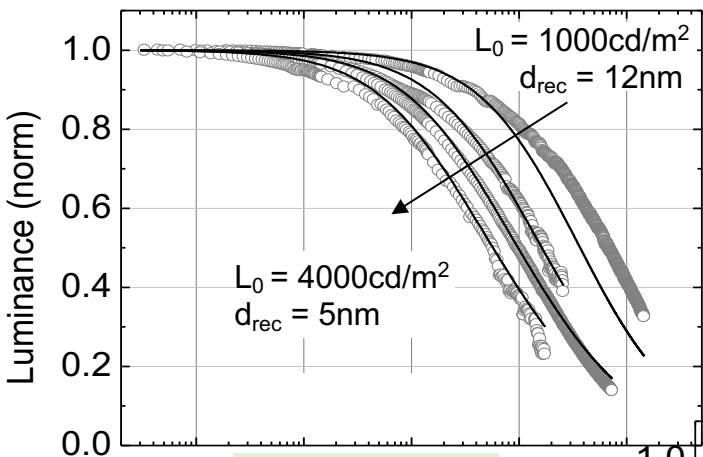


Exciton-Polaron Annihilation

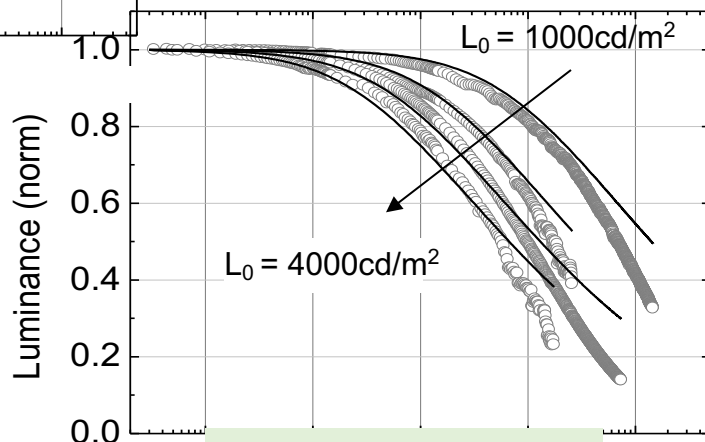
Triplet energy (~2.8 eV) + polaron (~3.3 eV) = hot polaron (≥ 6 eV)

Luminance Decay vs Time

- Blue PHOLED
- Prepared and packaged using industry std.

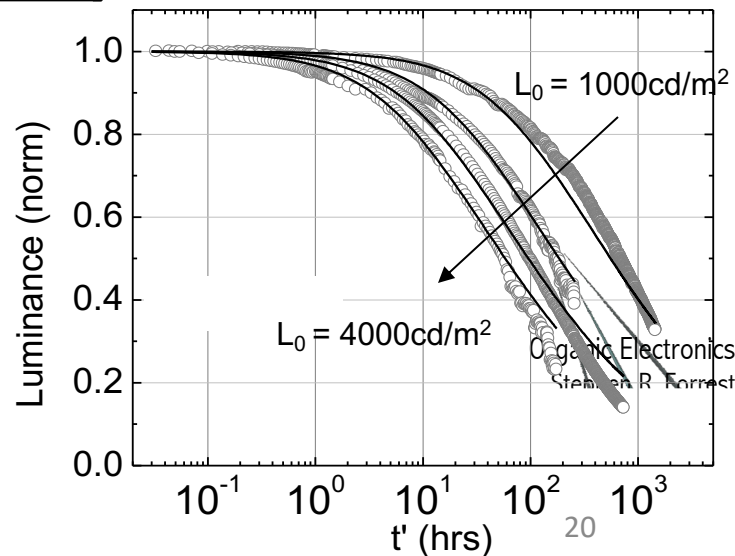


Exciton Localization



Exciton-Exciton Annihilation

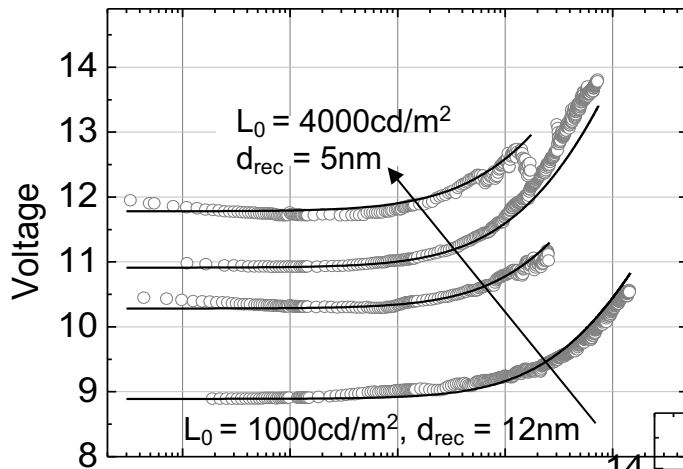
Exciton-Polaron Annihilation



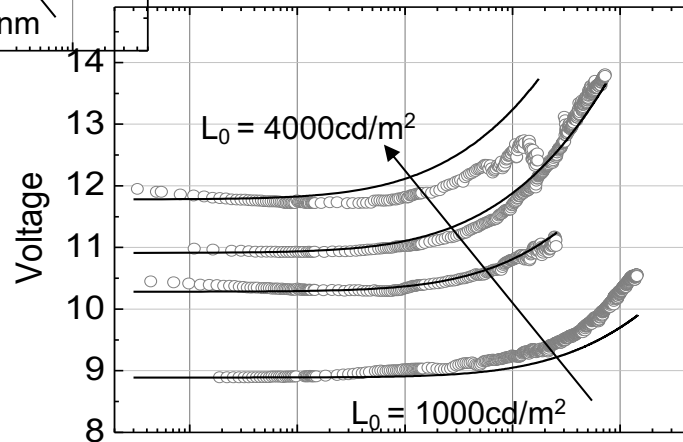
Defect Generation Rates

$$\frac{dQ(x,t')}{dt'} = \begin{cases} K_X n(x,t') & K_X p(x,t') & \text{P} \\ K_X N(x,t') & & \text{E} \\ K_X N^2(x,t') & & \text{E-E} \\ K_X N(x,t') n(x,t') & K_X N(x,t') p(x,t') & \text{E-P} \end{cases}$$

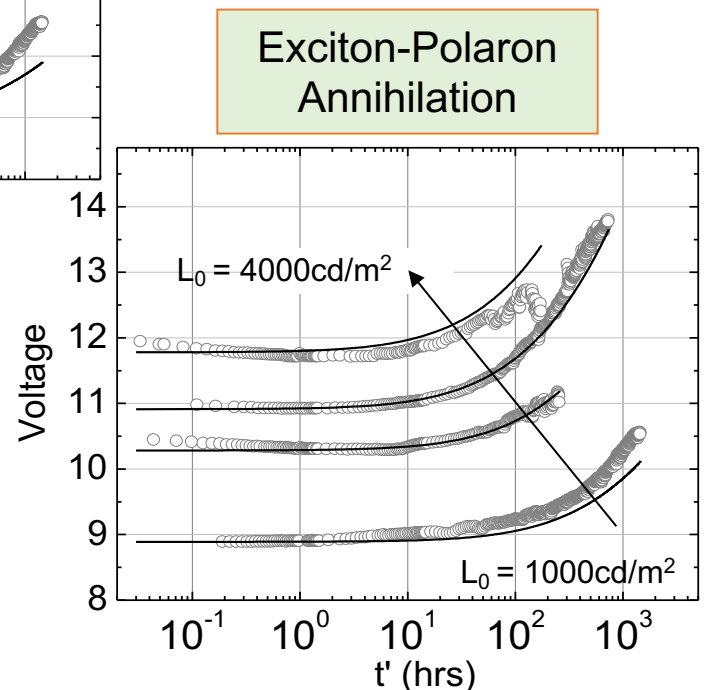
Drive Voltage Drift with Aging



Exciton
Localization



Exciton-Exciton
Annihilation

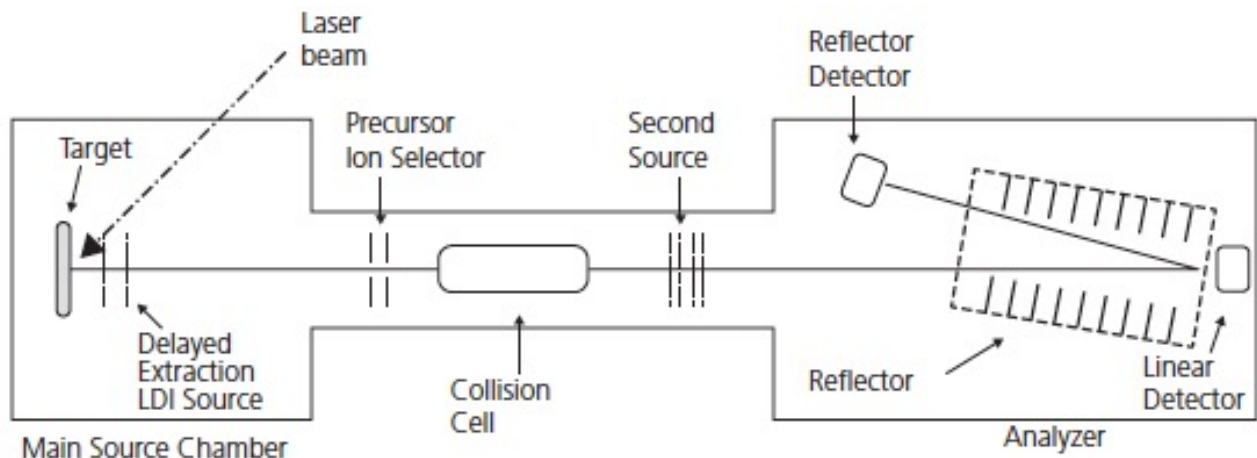


Exciton-Polaron
Annihilation

Conclusions

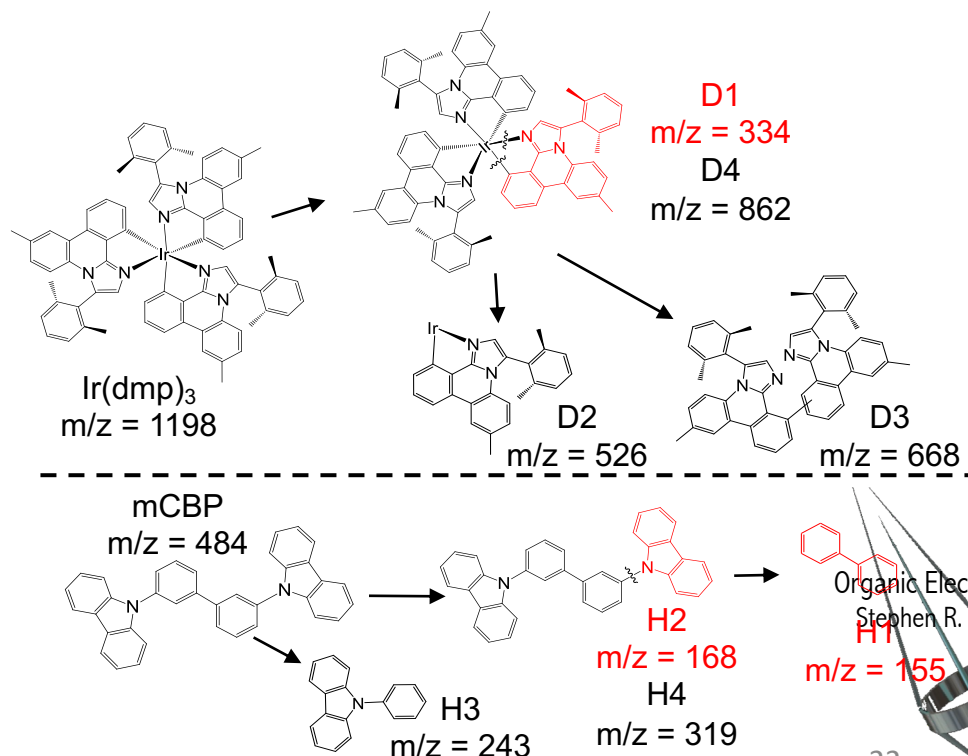
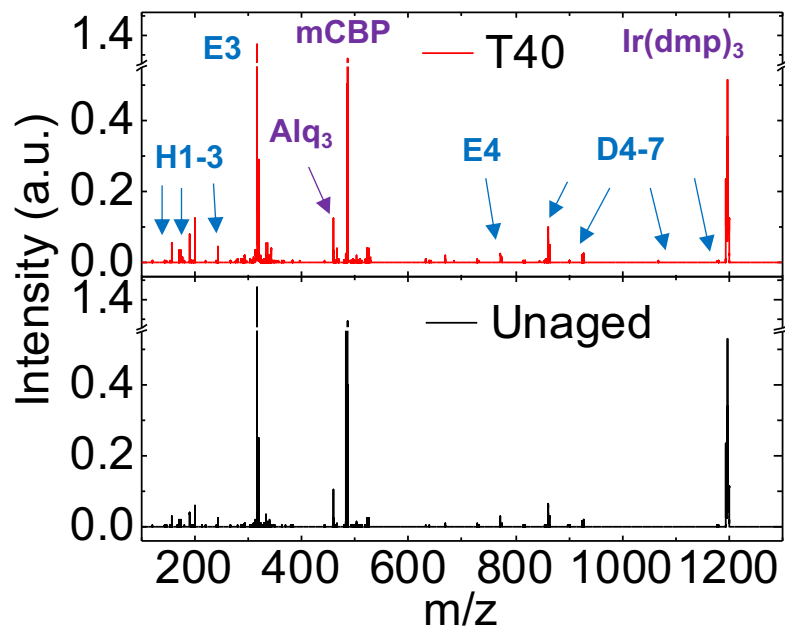
- $Q \sim 10^{18} \text{ cm}^{-3}$ → 50% increase in quenching
- At 1000 cd/m^2 , formation rate = $10^{12} \text{ cm}^{-2} \text{ s}^{-1}$
 - 1 in 5×10^8 E-P encounters leads to defect
 - Increasing recombination zone width extends lifetime
 - Guest triplets/host polarons most active

Evidence for Defect Formation: Molecular Fragmentation

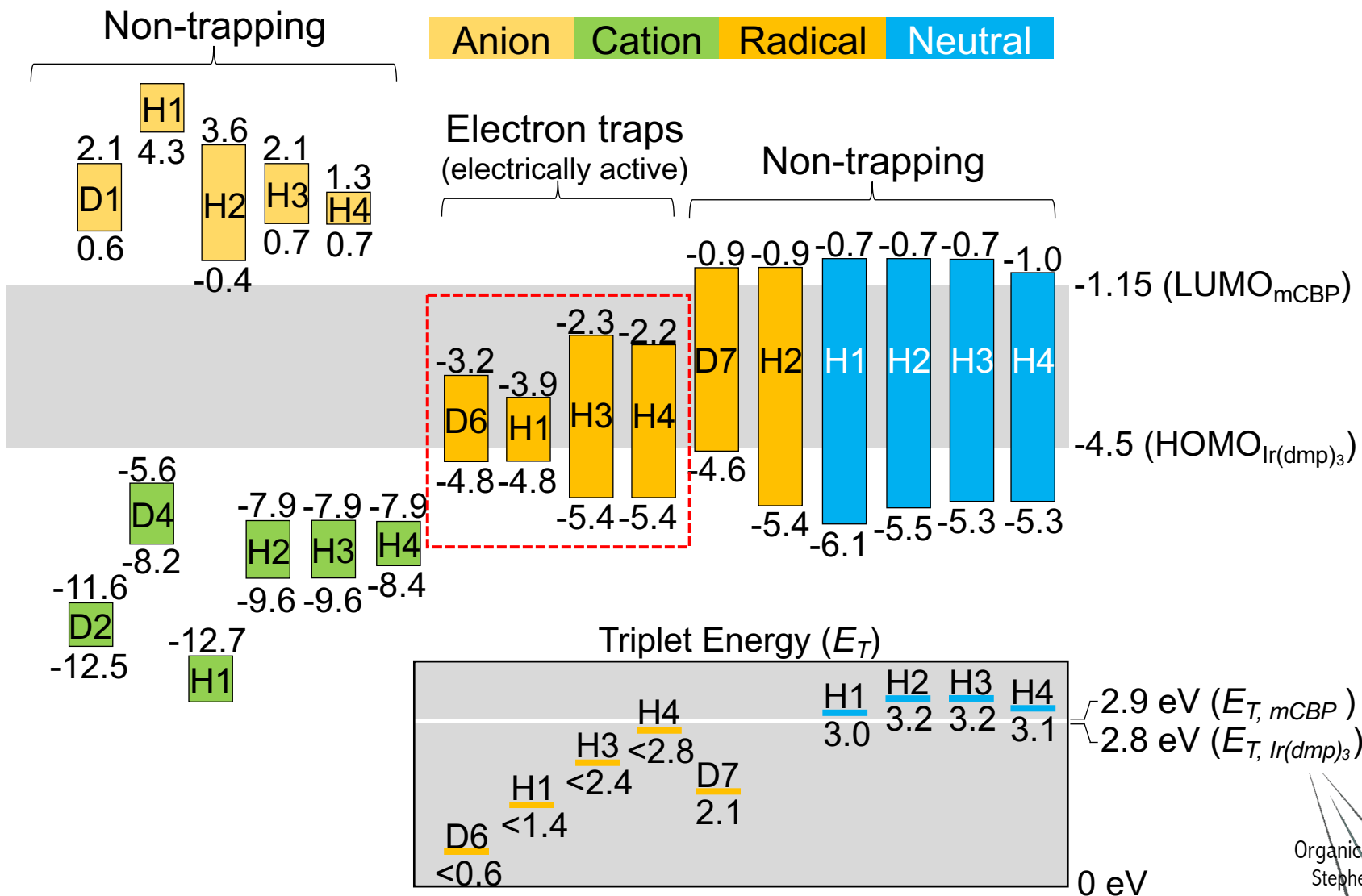


Laser Desorption Ionization-
Time of Flight Mass Spectroscopy
(LDI-TOF-MS)

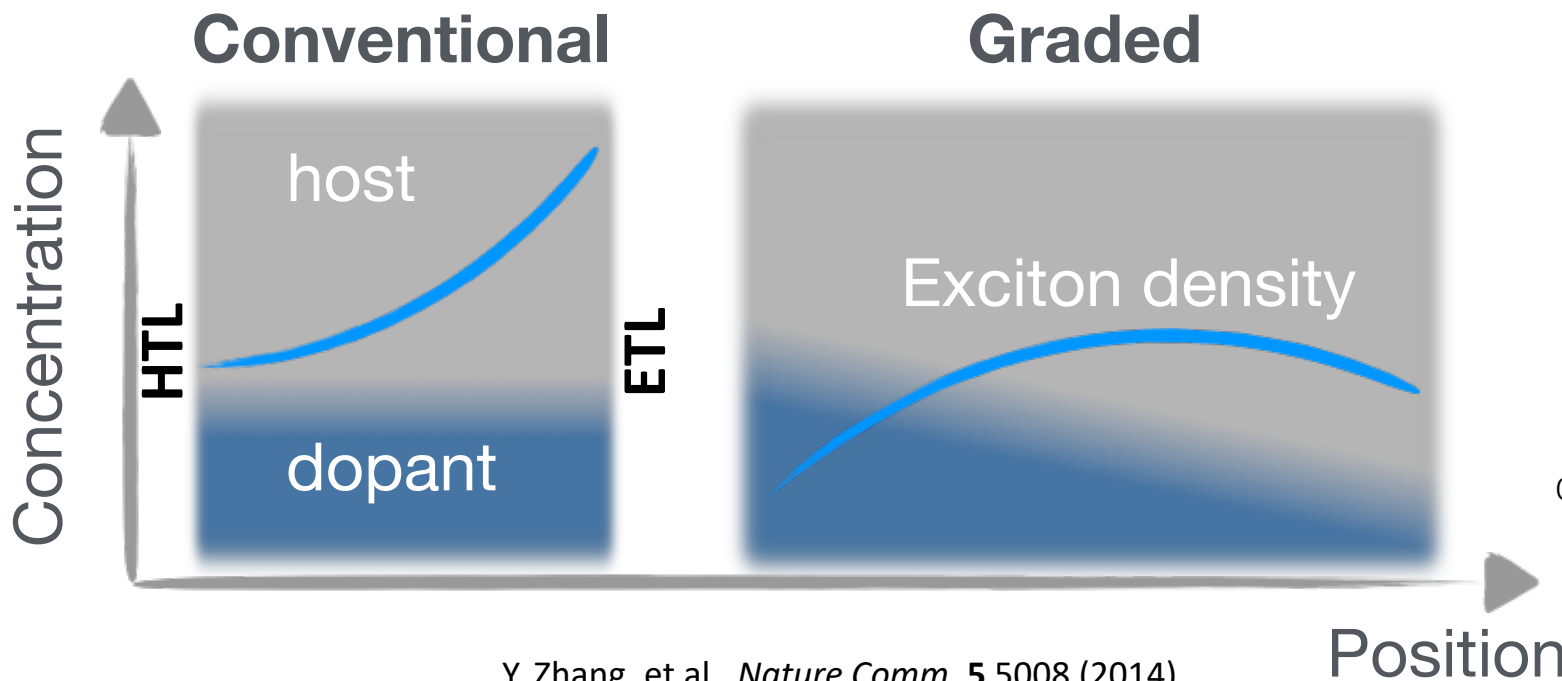
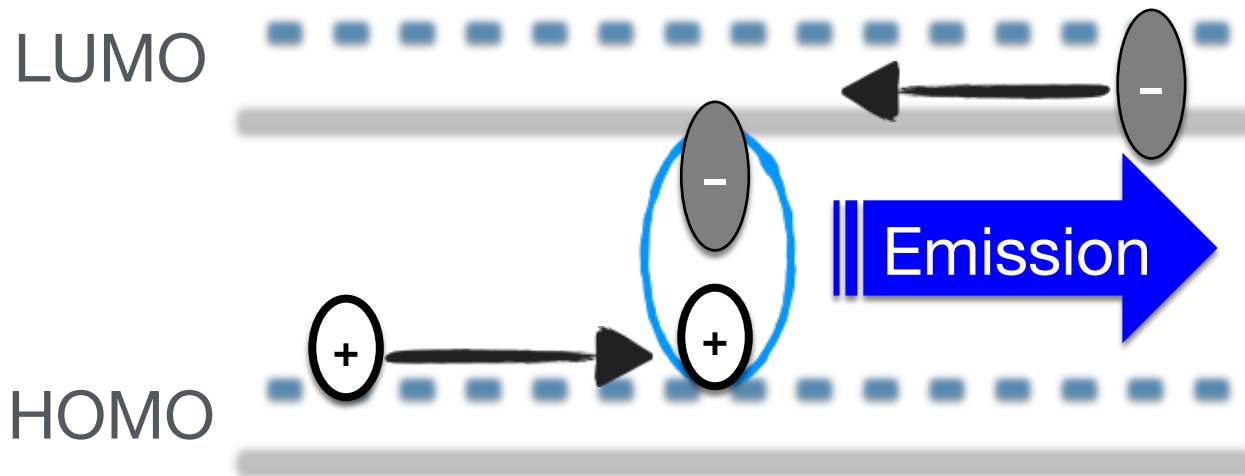
-Molecular species identification



Identification of Defect Energies

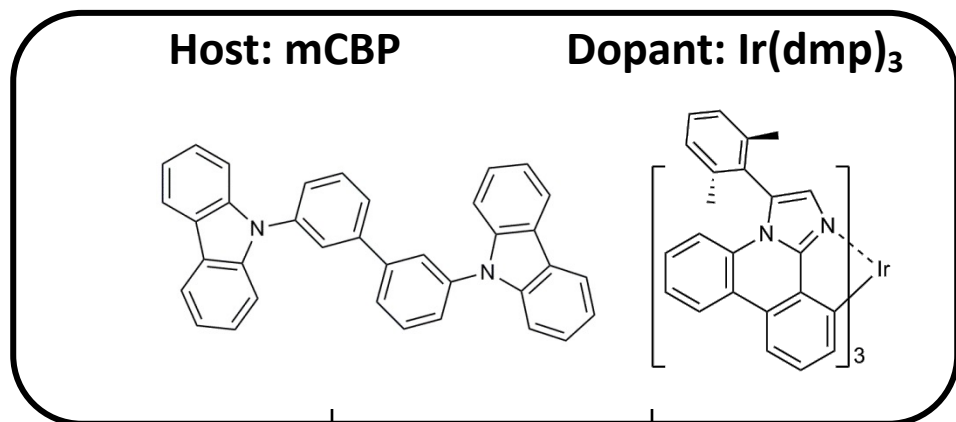


Reducing Exciton Density to Increase Lifetime



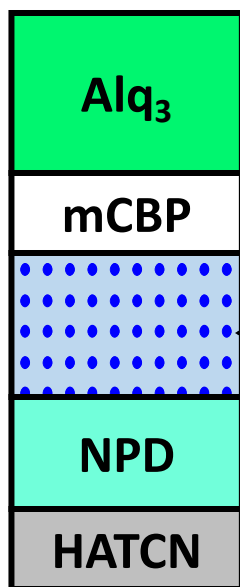
Spreading the recombination zone: Dopant/Host Grading

3 Different test device structures

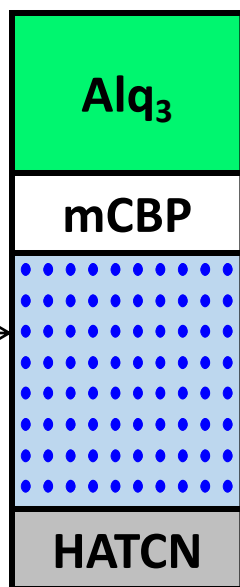


13 vol% uniform

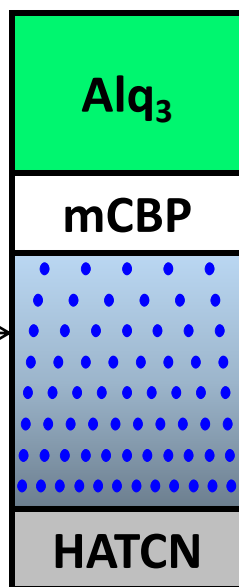
8 to 18% vol% graded



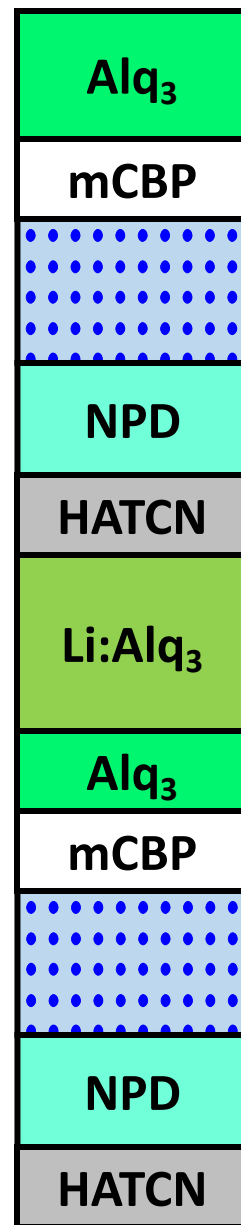
D1



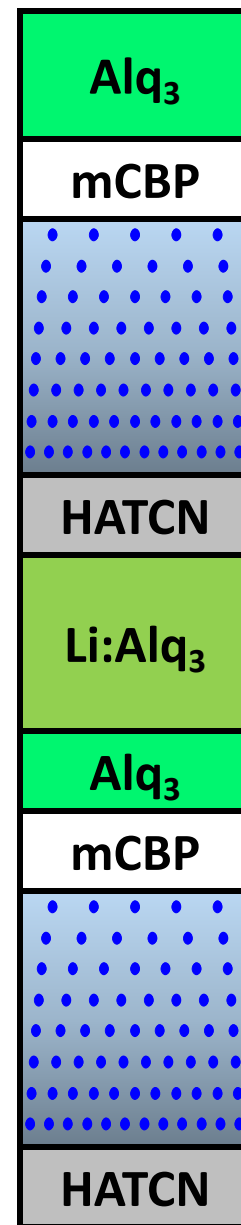
D2



D3

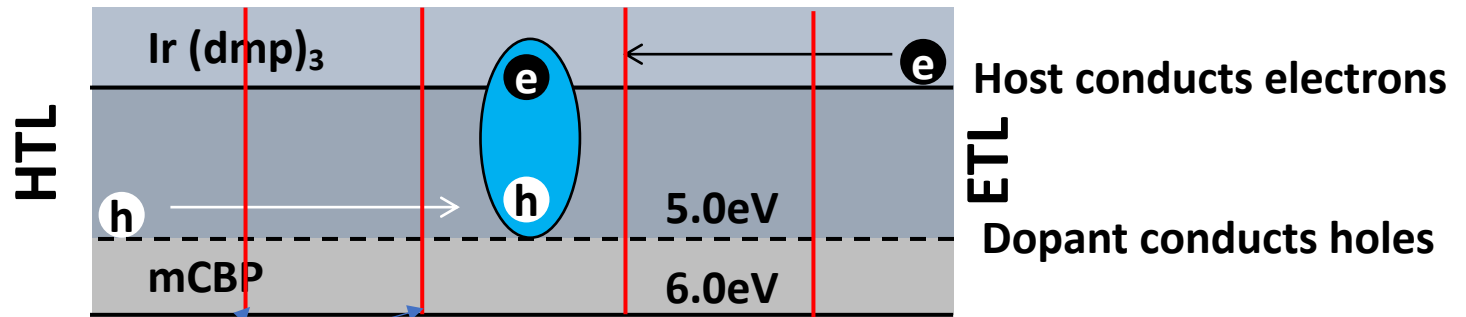


D1S

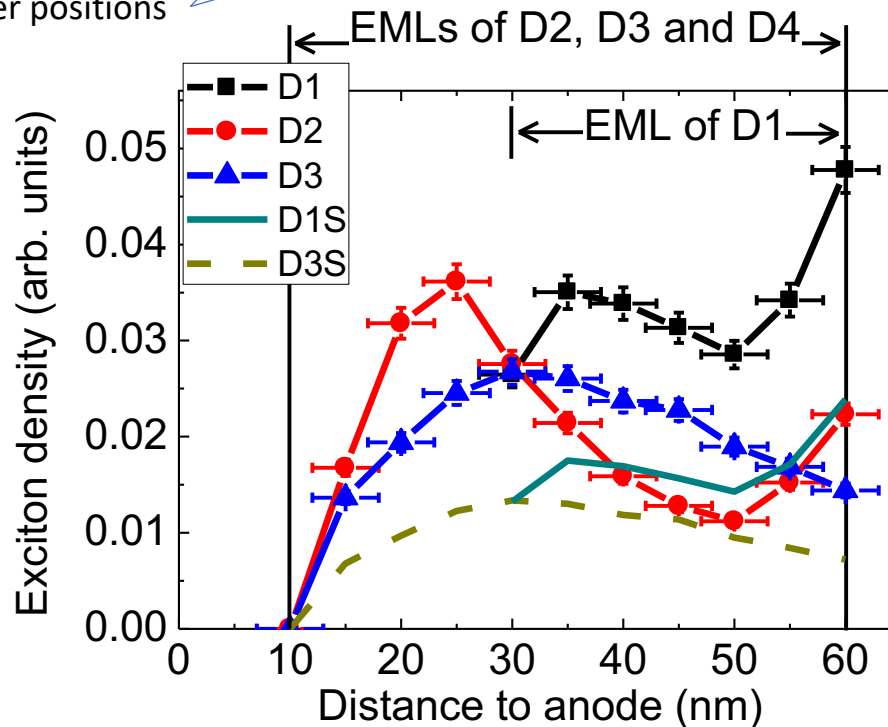


D3S

Excitons in the EML



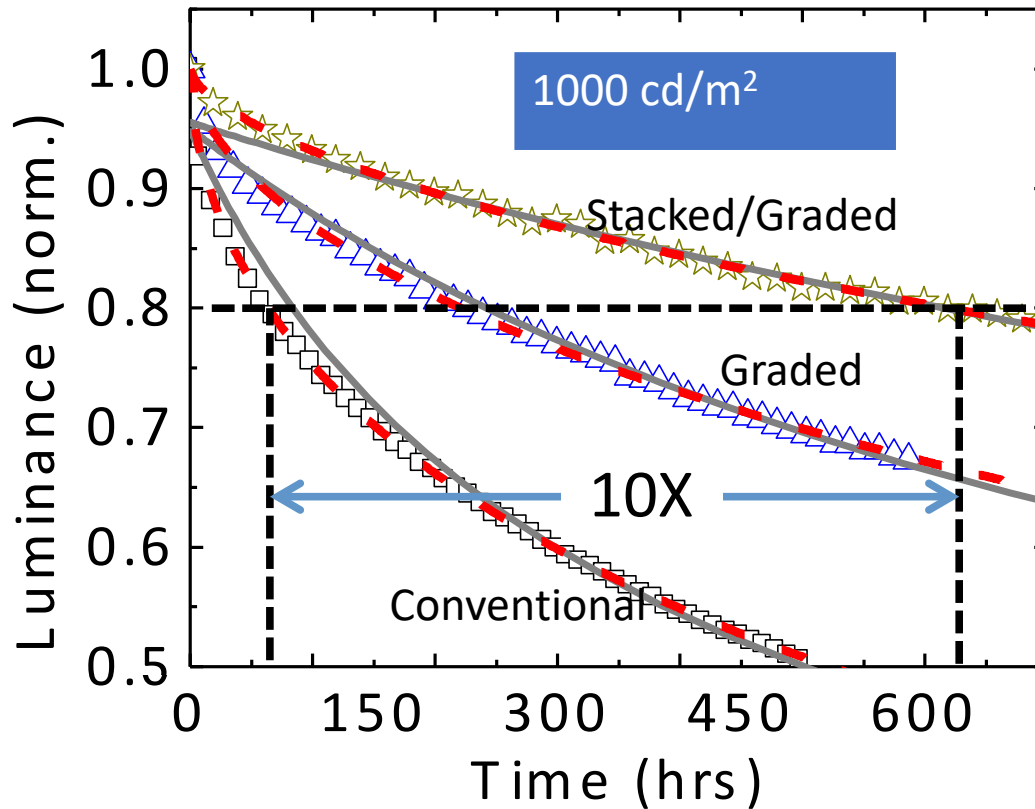
sensing layer positions



Exciton Sensing

- Red Phosphor (PQIr)
- 1.5 nm thick
- Placed at 5 nm intervals in EML
- Measure red emission intensity

10 X Lifetime Improvement Over Conventional



Stacking is essential!



Panel 15 cm x 15 cm 82% fill factor	2 Unit WSOLED
Luminance [cd/m ²]	3,000
Efficacy [lm/W]	48
CRI	86
Luminous Emittance [lm/m ²]	7,740
1931 CIE	(0.454, 0.426)
LT₇₀ [hrs]	13,000

Dopant Grading: Is it Good Enough?

using acceleration factors to predict lifetime

- Luminance to achieve sRGB color gamut for G is 10X that for B
- \Rightarrow B sub-pixel $L_0=100 \text{ cd/m}^2$ (c.f. G with $L_0>1,000 \text{ cd/m}^2$)
- \Rightarrow B lifetime to T50=70,000 hr.
- Adopting Degradation acceleration factor: $n = 1.55$ with

$$T50(100\text{cd/m}^2) = T50(1000\text{cd/m}^2) \times \left[\frac{1000\text{cd/m}^2}{100\text{cd/m}^2} \right]^n$$

- \Rightarrow B PHOLED lifetime to T50 = 1.3×10^5 hr.
- Commercial G PHOLED lifetime = 10^6 hours at $L_0 = 1000 \text{ cd/m}^2$.

Not blue enough, T95 is required

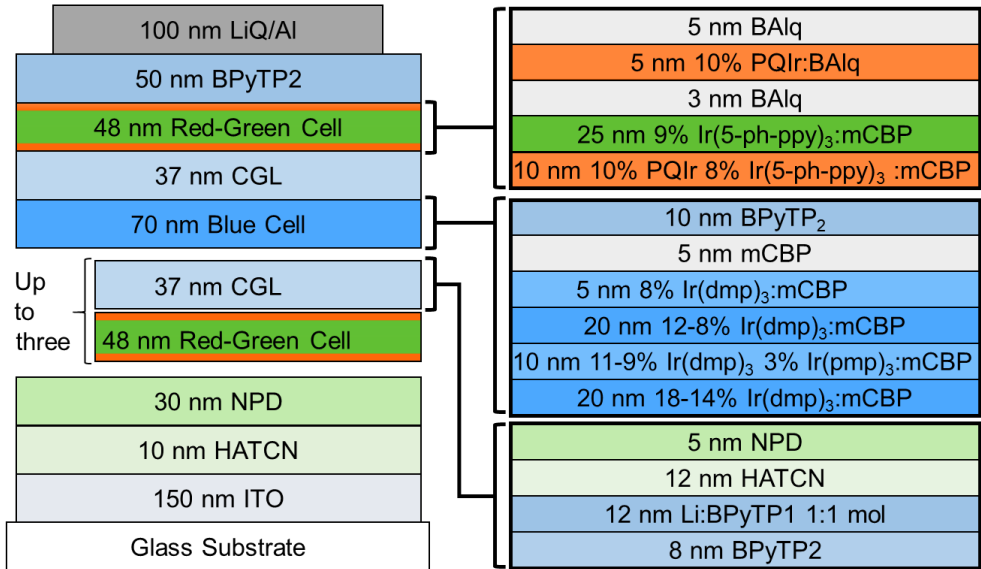


Dopant Grading for Lighting: Is it OK?

- Current state of stacked WOLED: T70=13,000 hrs
- Mostly limited by blue lifetime
- Only light blue required
- Estimated increase in lifetime for stacked blue at lighting brightness: ~4X
- Lifetime of blue lighting using grading: 50,000 hr

This is almost good enough

Putting Grading Excited State Management to Work: Long lived all phosphor stacked WOLEDs



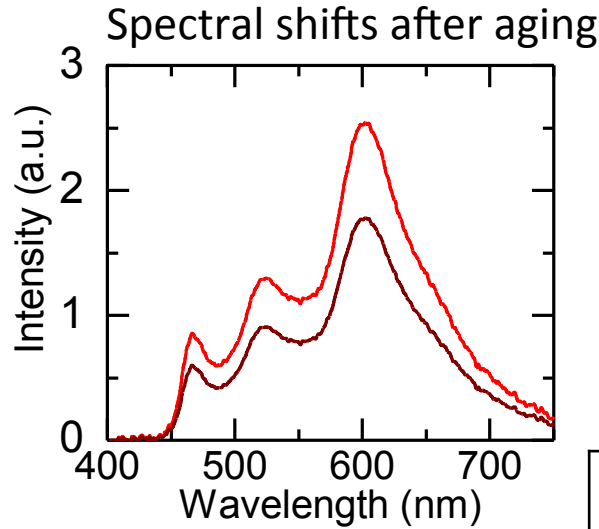
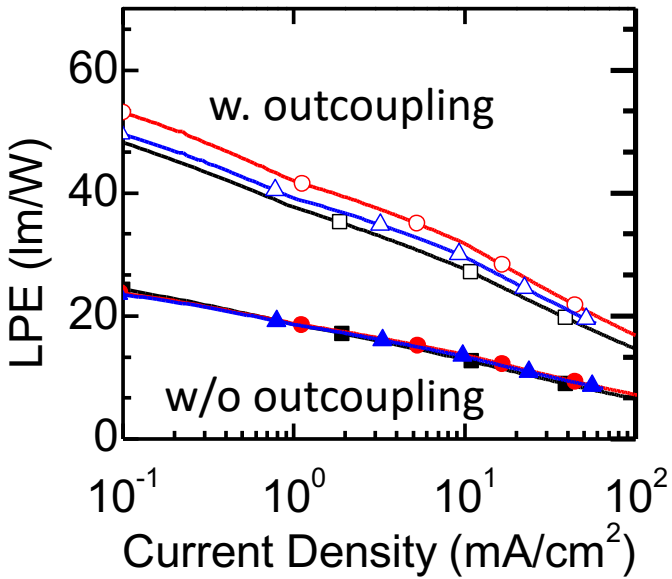
- Max Luminance > 200,000 nits
- 50 lm/W max
- CCT = 2780K
- CRI=89



Photo illustrating good color rendering of the SWOLEDs in this report. The luminaire comprises 36 pixels (2 mm²) operated at 50-100k nits



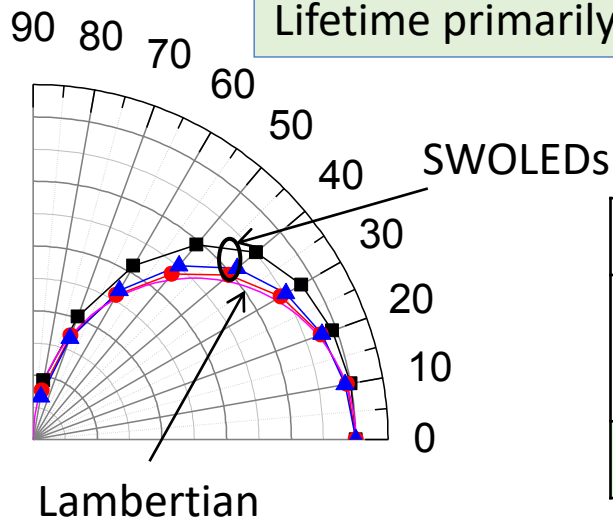
All Phosphor SWOLED Performance



T70	SWOLED
Δ CCT	-360 K
Δ CRI	-0.8
Δ CIE	(0.03,0)

SWOLED Architecture	Blue degradation @ WOLED T70:
Conv	T28
Grad-Managed	T48

Lifetime primarily limited by R/G sections



	With outcoupling		$\Delta V/V_0$ (T70) (%)
	T70 1000 nit (x10 ³ hr)	T70 3000 nit (x10 ³ hr)	
SWOLED	80±40	14±5	~+10%

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What we learned about OLEDs

- Chromaticity and the perception of color is quantified based on eye response (photometric quantities)
- OLEDs reach highest efficiency when both singlets and triplets are harvested (heavy metal complexes and TADF molecules)
- Optimized OLEDs have many layers serving purposes ranging from charge conduction, contacting to electrodes, to light emission
- Outcoupling methods essential to view substrate and waveguide modes while limiting surface plasmons
- Degradation of OLEDs particularly severe for blue due to bimolecular annihilation
- Lighting requires broad spectral emission using multilayer devices or excimer emission
- OLEDs provide uniform, area lighting vs. specular LED lighting

